

TRON

Real Time Testing

using UPPAAL

With

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BRICS

Basic Research
in Computer Science



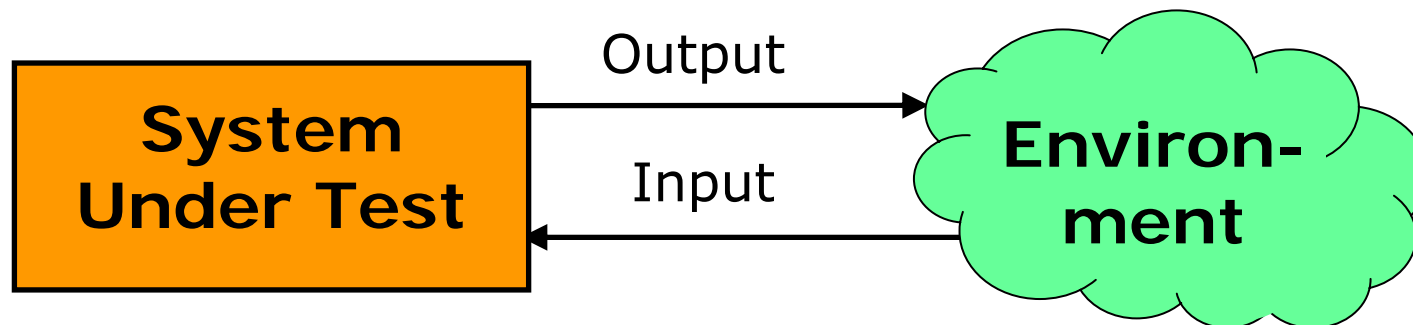
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Overview

- Introduction
- Conformance for Real-Time System
- Off-line Test Generation
 - Controllable Timed Automata **CLASSIC** **CORA**
 - Observable Timed Automata **TIGA**
- On-line Test Generation **TRON**
- Conclusion and Future Work

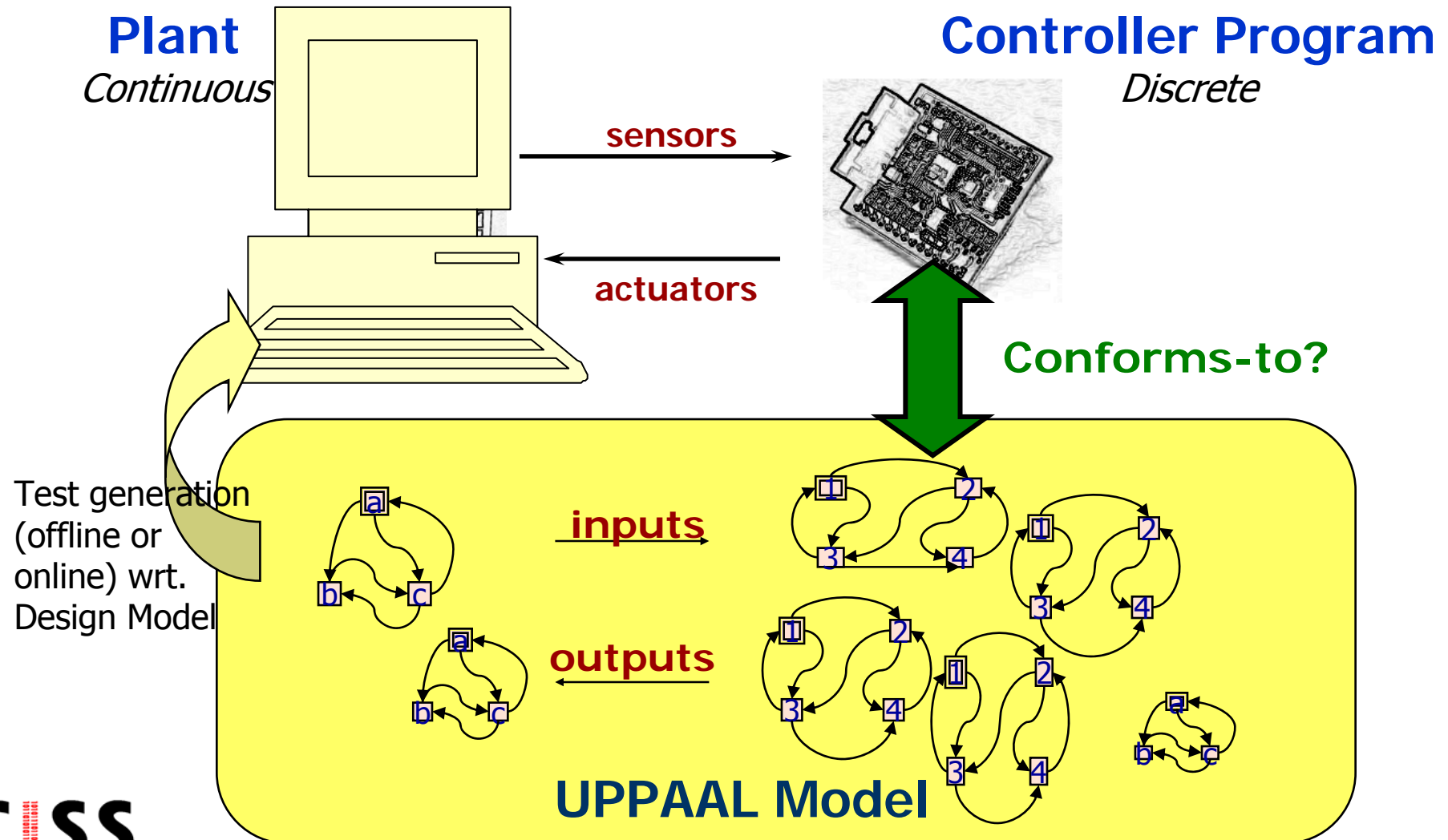
Testing

- Primary validation technique used in industry
 - In general avg. 10-20 errors per 1000 LOC
 - 30-50 % of development time and cost in embedded software
- To find errors
- To determine risk of release
- Part of system development life-cycle



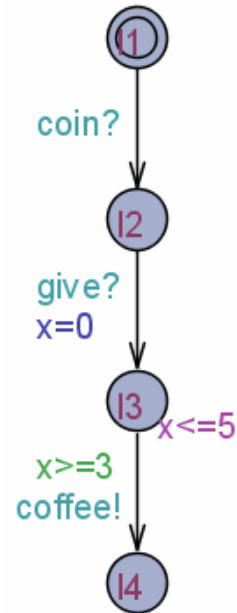
- Expensive, error prone, time consuming (for Real-Time Systems)
- UPPAAL model can be used to generate test specifications

Real-time Model-Based Testing

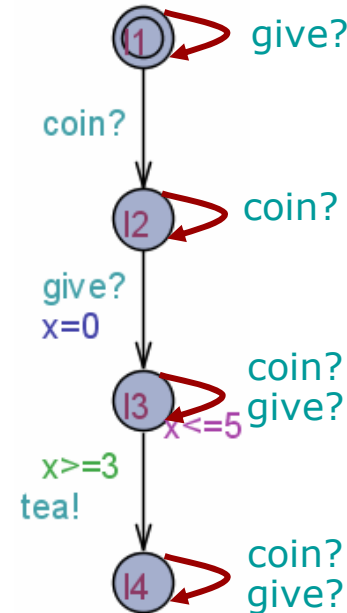


Conformance Relation

Specification

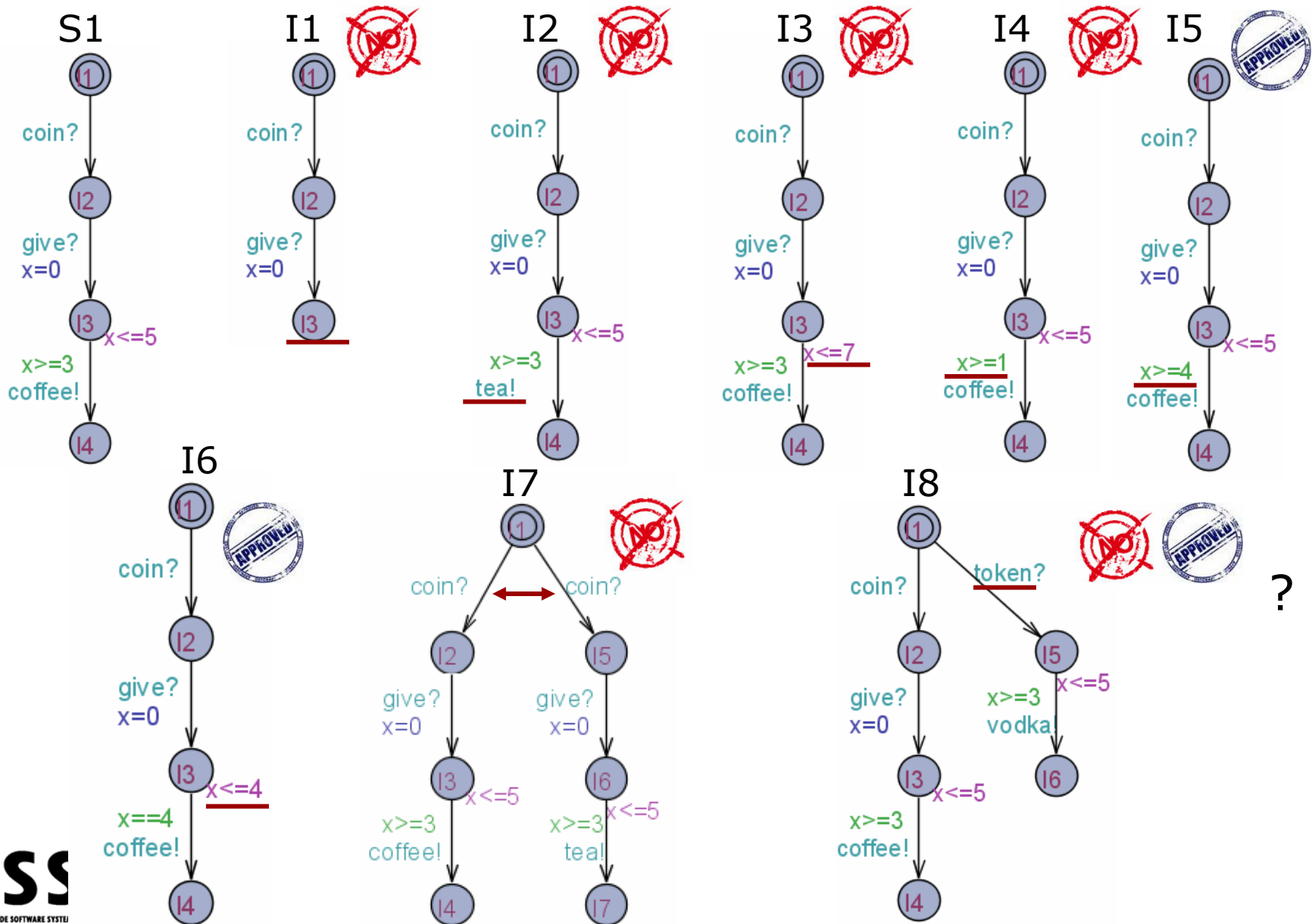


Implementation



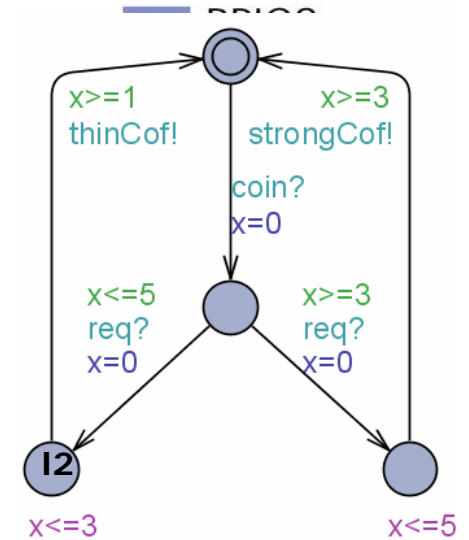
- Timed Automata with Timed-LTS semantics
- **Input** actions (?) are controlled by the environment
- **Output** actions (!) are controlled by the implementation
- Implementations are *input enabled*
- **Testing hypothesis:** IUT can be modeled by some (unknown) TA

Does I_n conform-to S_1 ?



Timed Conformance

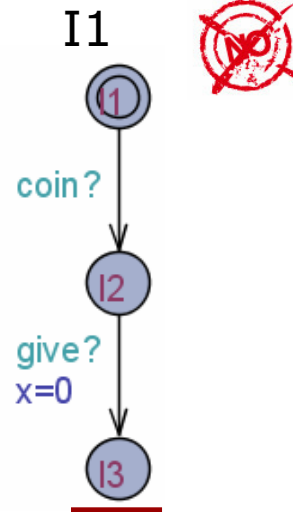
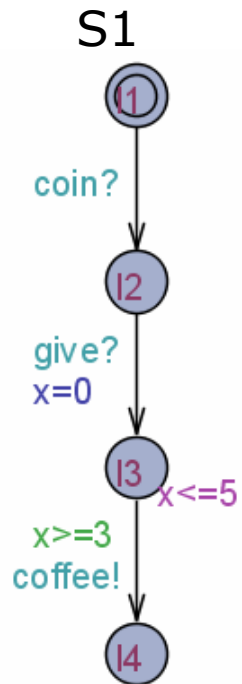
- Derived from Tretman's IOCO
- Let I, S be timed I/O LTS, P a set of states
- $TTr(P)$: the set of *timed traces* from P
 - eg.: $\sigma = \text{coin?}.5.\text{req?}.2.\text{thinCoffee!}.9.\text{coin?}$
- $\text{Out}(P \text{ after } \sigma) =$ possible *outputs* and *delays* after σ
 - eg. $\text{out}(\{l2, x=1\}) = \{\text{thinCoffee}, 0 \dots 2\}$



- **$I \text{ rt-ioco } S = \text{def}$**
 - $\forall \sigma \in TTr(S): \text{Out}(I \text{ after } \sigma) \subseteq \text{Out}(S \text{ after } \sigma)$
 - $TTr(I) \subseteq TTr(S)$ if s and I are input enabled

- **Intuition**
 - no illegal output is produced and
 - required output is produced (at right time)

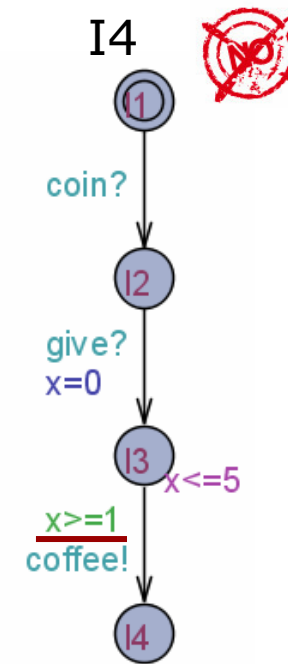
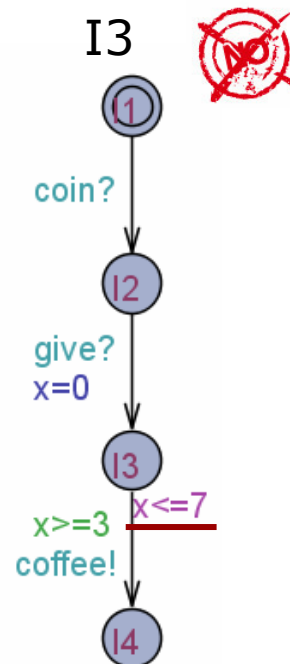
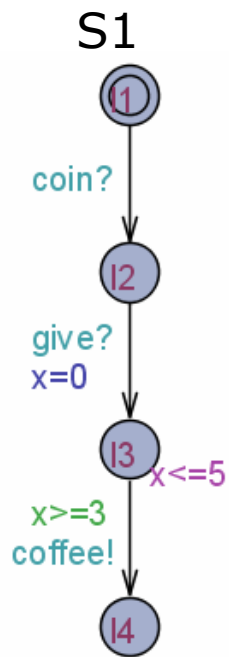
Does I_n conform-to S_1 ?



$\sigma = \text{coin.give.10}$
 $\sigma \in \text{TTr}(I1), \sigma \notin \text{TTr}(S1)$

$\text{out}(I1 \text{ after coin.give.3}) = \{0 \dots \infty\}$
 $\not\subseteq$
 $\text{out}(S1 \text{ after coin.give.3}) = \{\text{coffee}, 0 \dots 2\}$

Does I_n conform-to S_1 ?



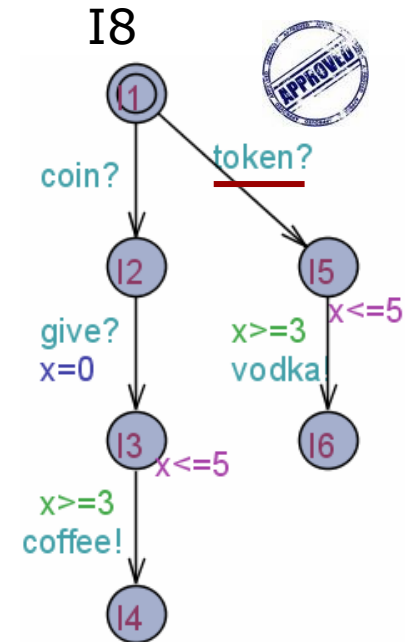
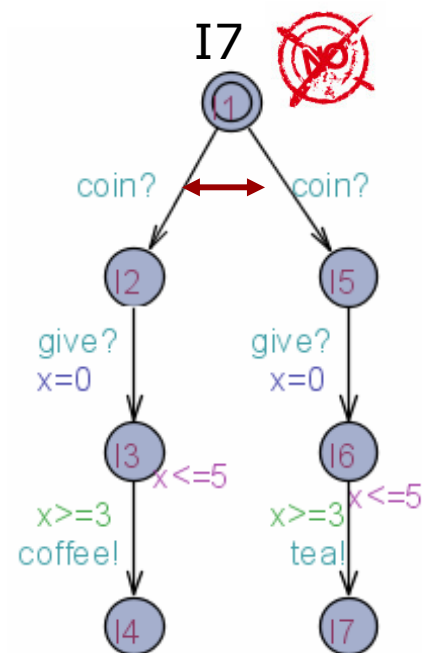
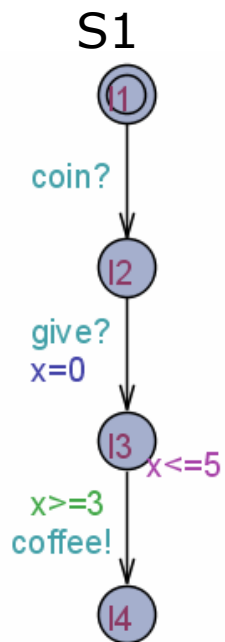
$\sigma = \text{coin.give.7.coffee}$
 $\sigma \in \text{TTr}(I3), \sigma \notin \text{TTr}(S1)$

$\text{out}(I3 \text{ after coin.give.7}) = \{\text{coffee}, 0\}$
 $\not\subseteq$
 $\text{out}(S1 \text{ after coin.give.7}) = \{\}$

$\sigma = \text{coin.give.1.coffee}$
 $\sigma \in \text{TTr}(I4), \sigma \notin \text{TTr}(S1)$

$\text{out}(I4 \text{ after coin.give.1}) = \{\text{coffee}, 0 \dots 4\}$
 $\not\subseteq$
 $\text{out}(S1 \text{ after coin.give.1}) = \{0 \dots 4\}$

Does I_n conform-to S_1 ?



$\sigma = \text{coin.give.5.tea}$
 $\sigma \in \text{TTr}(I7), \sigma \notin \text{TTr}(S1)$

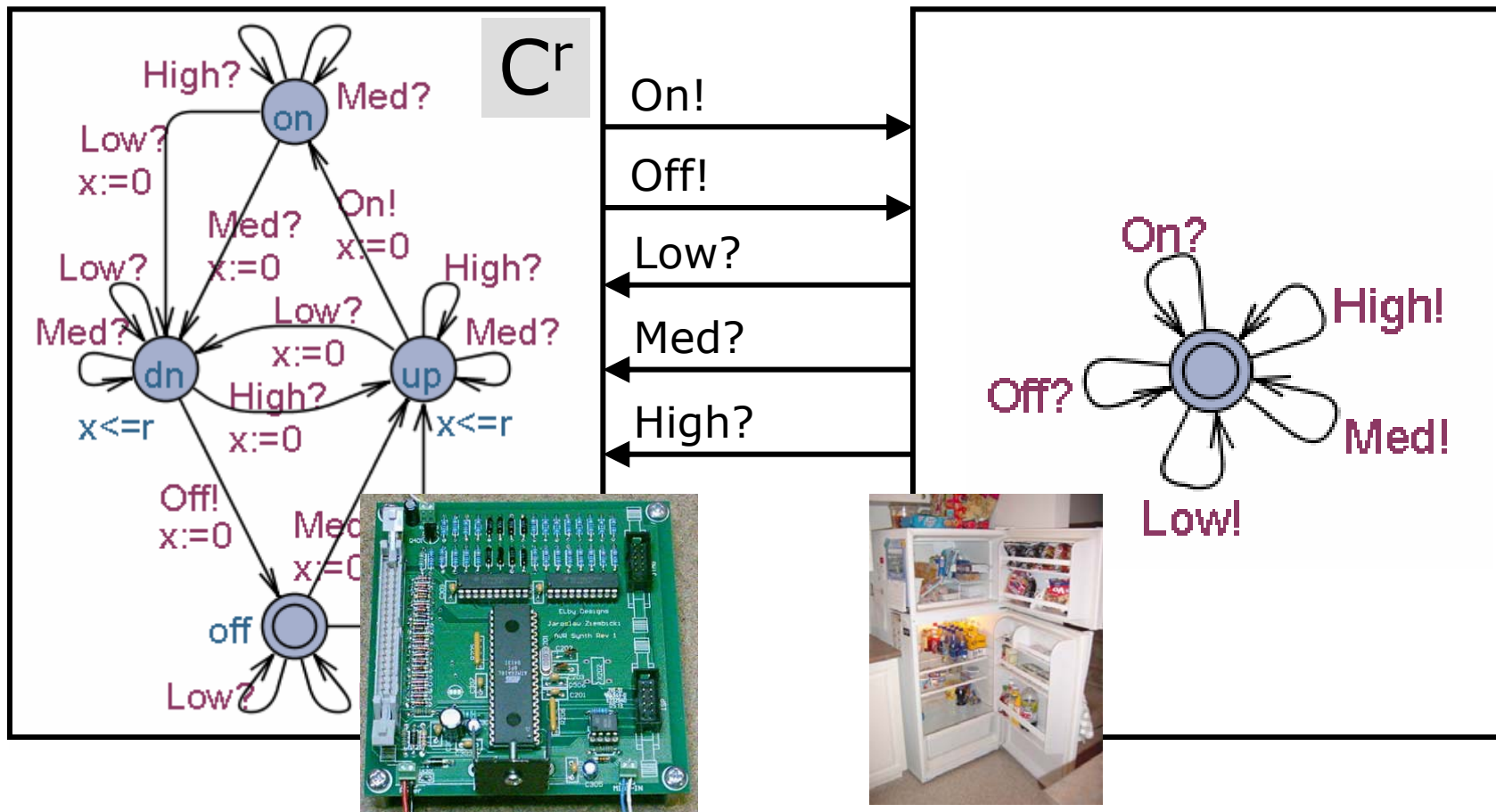
$\sigma = \text{token.5.vodka}$
 $\sigma \in \text{TTr}(I8), \sigma \notin \text{TTr}(S1)$
But σ was not specified

$\text{out}(I7 \text{ after coin.give.5}) = \{\text{tea, coffee}, 0\}$
 \neq
 $\text{out}(S1 \text{ after coin.give.5}) = \{\text{coffee}, 0\}$

Sample Cooling Controller

IUT-model

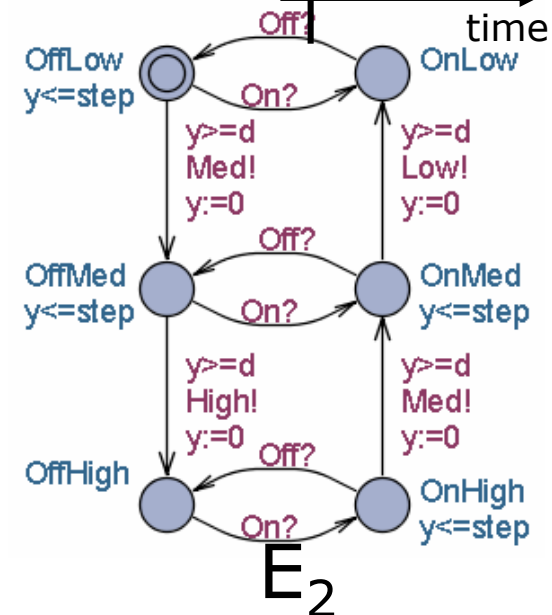
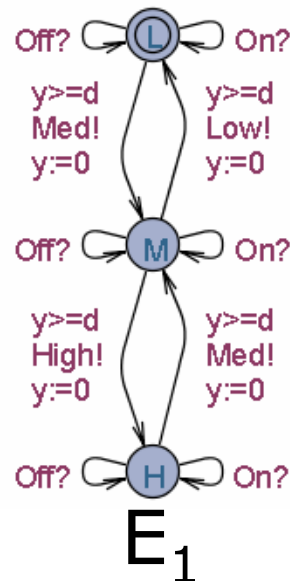
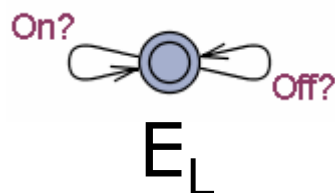
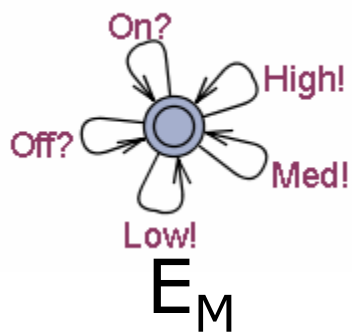
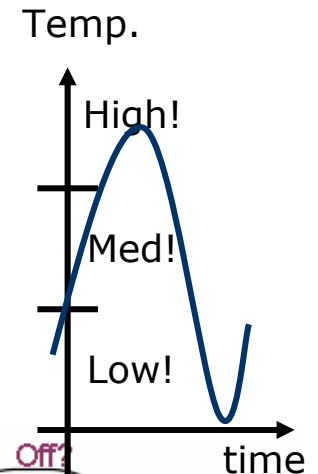
Env-model



- When T is high (low) switch on (off) cooling within r secs.
- When T is medium cooling may be either on or off (impl freedom)

Environment Modeling

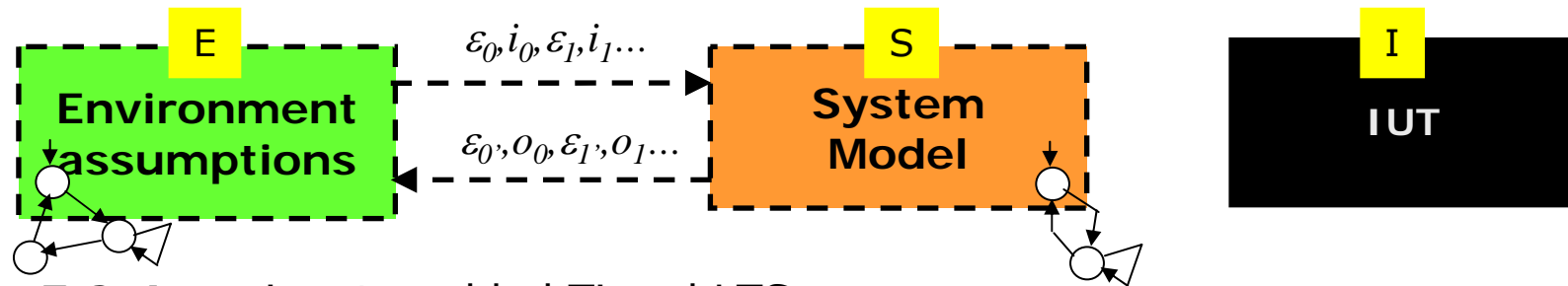
- E_M Any action possible at any time
- E_1 Only realistic temperature variations
- E_2 Temperature never increases when cooling
- E_L No inputs (completely passive)



$$E_L \subseteq E_2 \subseteq E_1 \subseteq E_M$$

Implementation relation

Relativized **real-time io-conformance**



- **E, S, I** are input enabled Timed LTS
- Let P be a set of states
- $TTr(P)$: the set of *timed traces* from states in P
- P after σ = the set of states reachable after timed trace σ
- $Out(P)$ = possible outputs and delays from states in P

- $I \text{ rt-ioco}_E S =_{\text{def}} \forall \sigma \in TTr(E): Out((E, I) \text{ after } \sigma) \subseteq Out((E, S) \text{ after } \sigma)$
- $I \text{ rt-ioco}_E S$ iff $TTr(I) \cap TTr(E) \subseteq TTr(S) \cap TTr(E)$ // *input enabled*

- **Intuition, for all assumed environment behaviors, the IUT**
 - never produces illegal output, and
 - always produces required output in time

Re-use Testing Effort

- Given I, E, S
 - Assume $I \text{ rt-ioco}_E S$
1. Given new (weaker) system specification S'

If $S \sqsubseteq S'$ then $I \text{ rt-ioco}_E S'$

2. Given new (stronger) environment specification E'

If $E' \sqsubseteq E$ then $I \text{ rt-ioco}_{E'} S$

Off-Line Test Generation

*Controllable
Timed Automata*



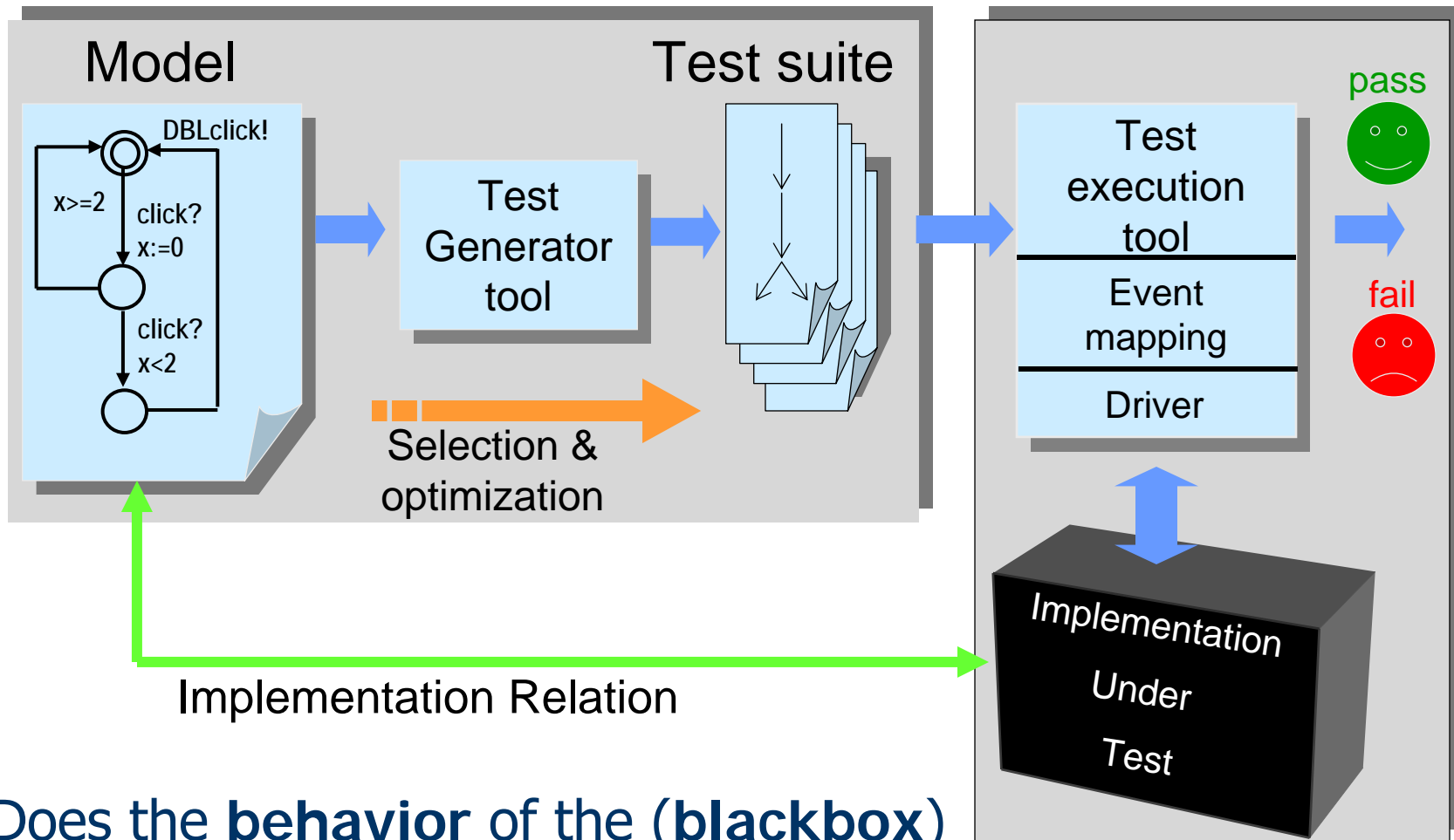
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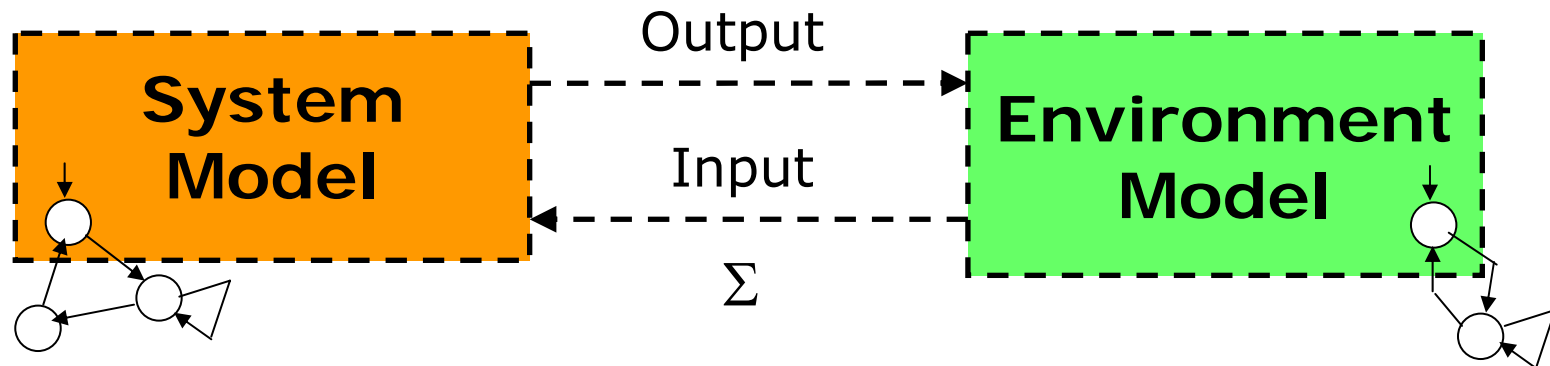
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Model Based Conformance Testing



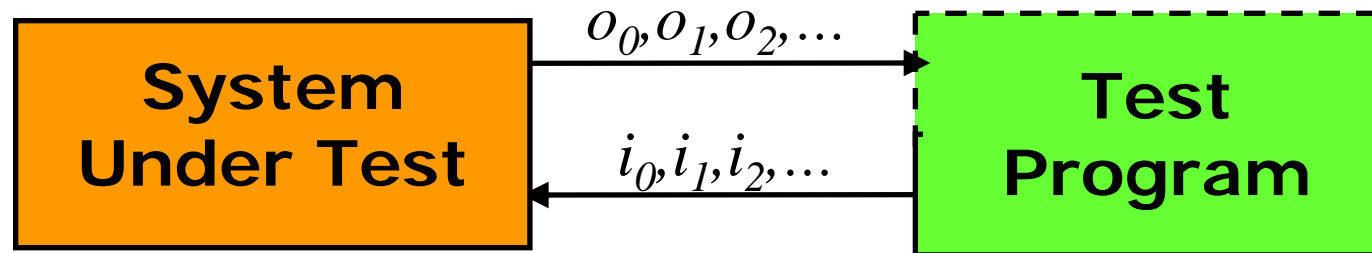
Does the **behavior** of the (**blackbox**) implementation *comply* to that of the specification?

Model-Based Testing



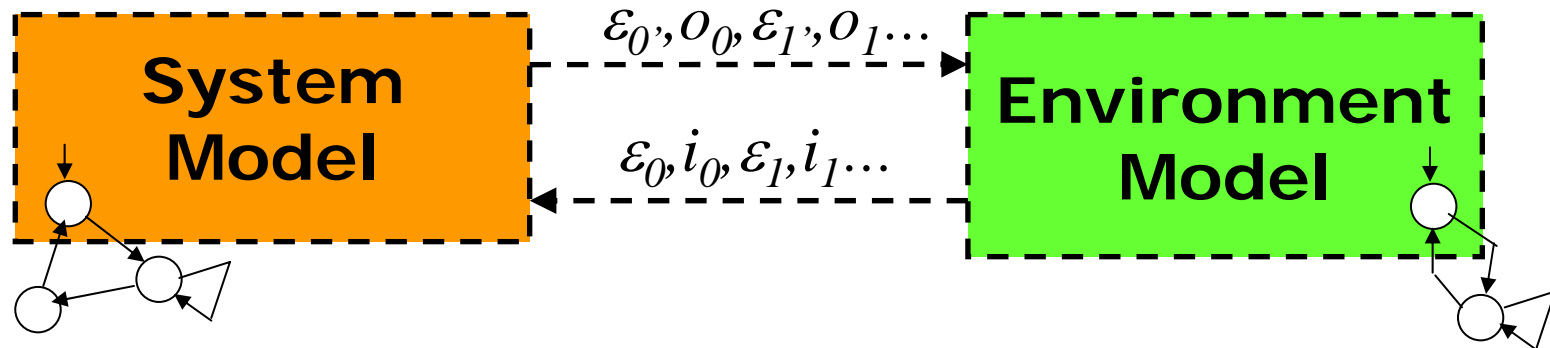
- FSM model of system and environment
- Determinizable/deterministic models
- Test purpose $P \approx$ reachability property ϕ_P
- Test-case generation \approx witness generation
- Test input sequence $\sigma_{\phi_P} = i_0, i_1, i_2, \dots$
- Test suite $T = \{\sigma_1, \dots, \sigma_n\}$, minimized by excluding all σ_i substring of some other σ_j

Testing Verdict



- Test program $\sigma_{\phi p} = i_0, i_1, i_2, \dots$
- Test in/output $\delta_{\phi p} = i_0, o_0, i_1, o_1, i_2, i_3, \dots$
- Test Verdict:
 - OK, if $\delta_{\phi p} = i_0, o_0, i_1, o_1, i_2, i_3, \dots$ run of system model
 - NOK, otherwise

Testing Real-Time Systems



- Test input sequence $\sigma_{\phi p} = \varepsilon_0, i_0, \varepsilon_1, i_1, \varepsilon_2, i_2, \dots$
- Test in/output $\delta_{\phi p} = \varepsilon_0, i_0, \varepsilon_1, o_0, \varepsilon_1, i_1, o_1, \dots$
- Test Verdict:
 - OK, if $\delta_{\phi p} = \varepsilon_0, i_0, \varepsilon_1, o_0, \varepsilon_1, i_1, o_1, \dots$ run of system model
 - NOK, otherwise
- Timed Automata?

This work

- Test case generation from timed automata
 - by reachability analysis
 - implementation in UPPAAL
- Testing Criteria:
 - single test purpose
 - coverage criteria: location, branching, definition/use pairs, etc.
- Optimality:
 - Test Cases: $\sigma_{\phi p} = \varepsilon_0, i_0, \varepsilon_1, i_1, \varepsilon_2, i_2, \dots$ with minimum cost
e.g. $\min(\varepsilon_0 + \varepsilon_1 + \dots + \varepsilon_n)$
 - Test Suites: $T = \{ \sigma_1, \dots, \sigma_n \}$ with minimum cost

Controllable Timed Automata

Input Enabled:

all inputs can always be accepted.

Assumption about
model of SUT

Output Urgent:

enabled outputs will occur immediately.

Determinism:

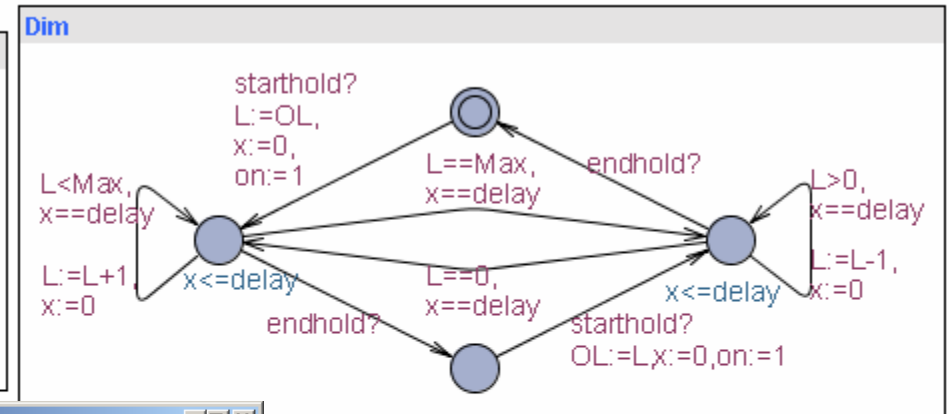
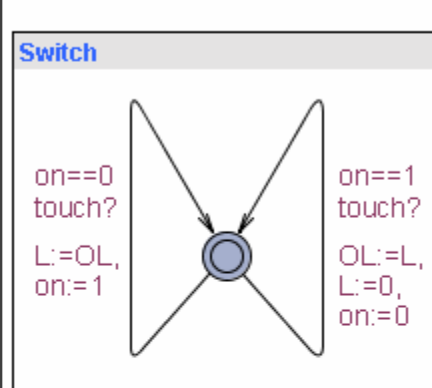
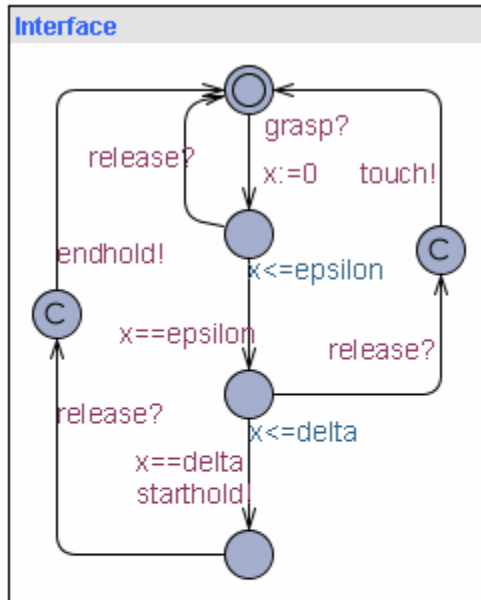
two transitions with same input/output leads to the same state.

Isolated Outputs:

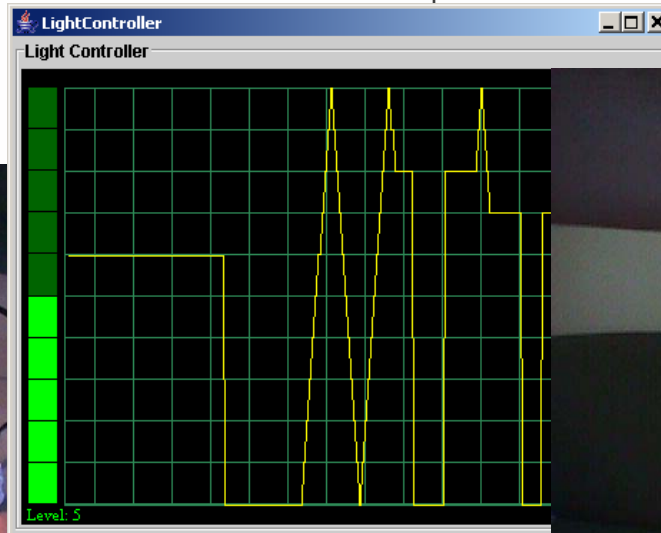
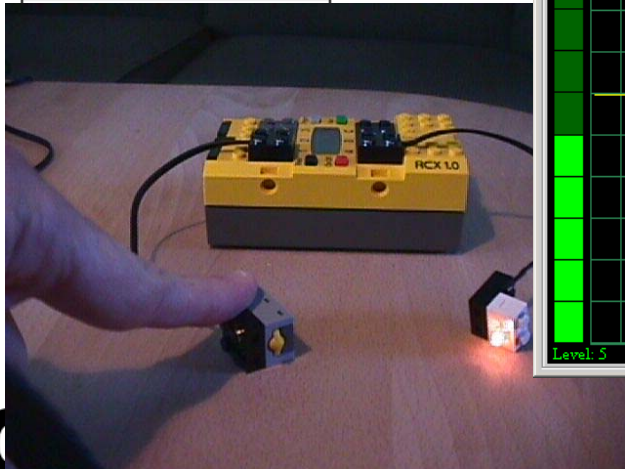
if an output is enabled, no other output is enabled.

Example

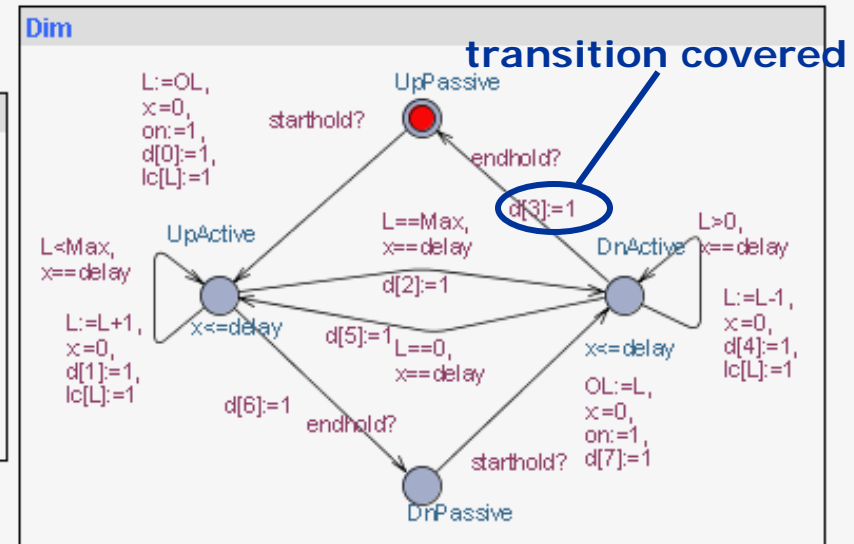
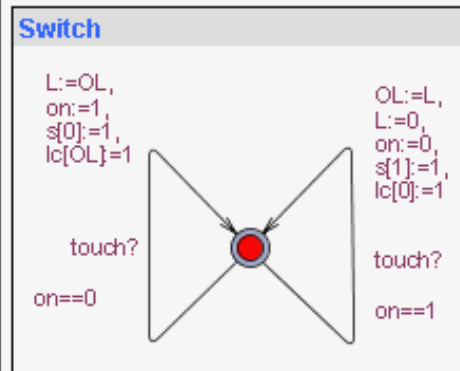
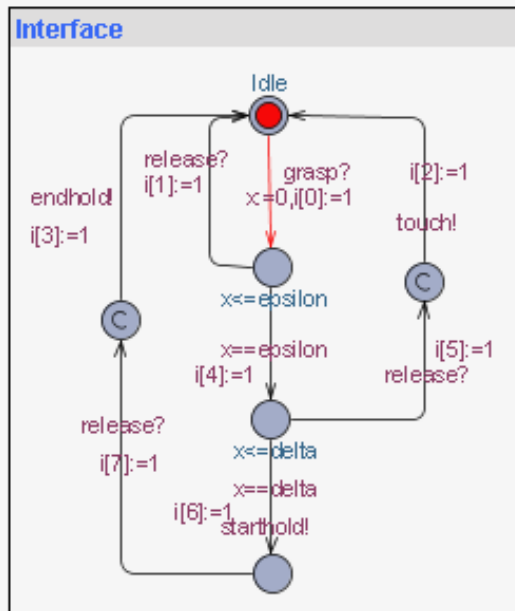
Light Controller



User



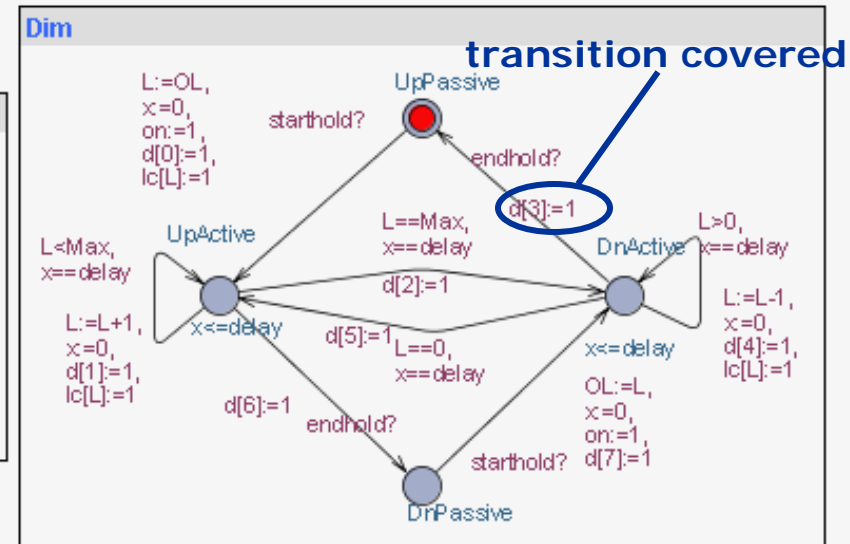
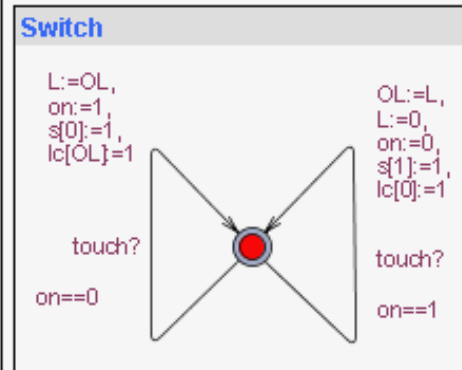
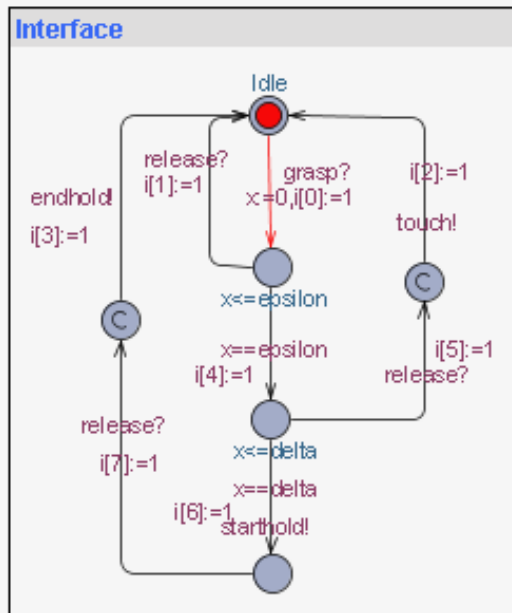
Off-Line Testing = Optimal Reachability



- Specific Test Purposes
- Model Coverage
- Optimal test-suites

Off-Line Testing = Optimal Reachability

Fastest Transition Coverage = 12600 ms



```

out(IGrasp);           //touch:switch light on
silence(200);
out(IRelease);
in(OSetLevel,0);

out(IGrasp); // @200 // touch: switch light off
silence(200);
out(IRelease); // touch
in(OSetLevel,0);

//9
out(IGrasp); // @400 //Bring dimmer from ActiveUp
silence(500); //hold //To Passive DN (level=0)
in(OSetLevel,0);
out(IRelease);
    
```

Page 1

```

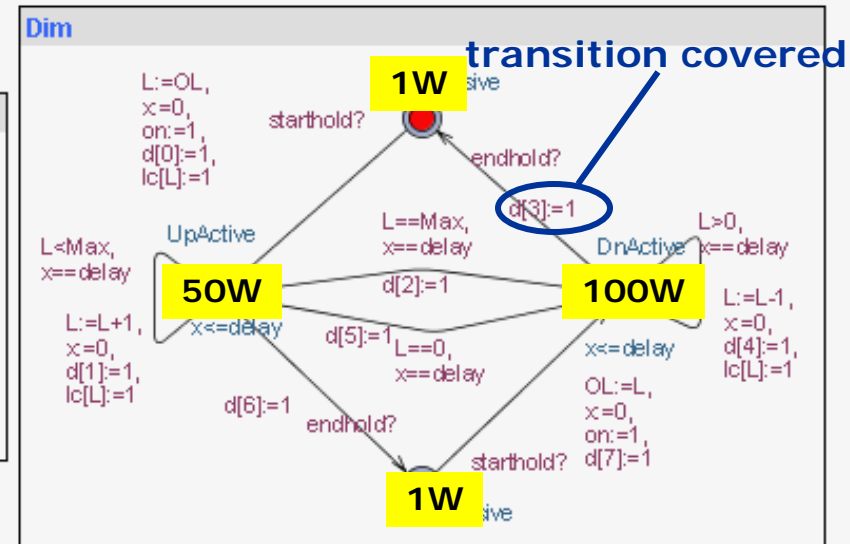
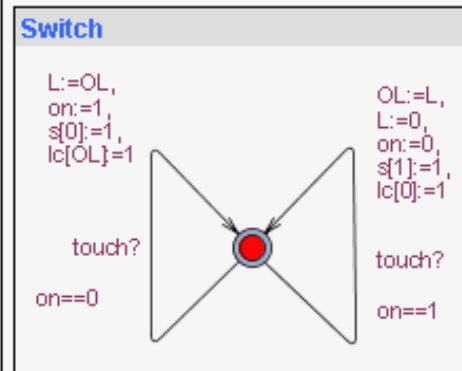
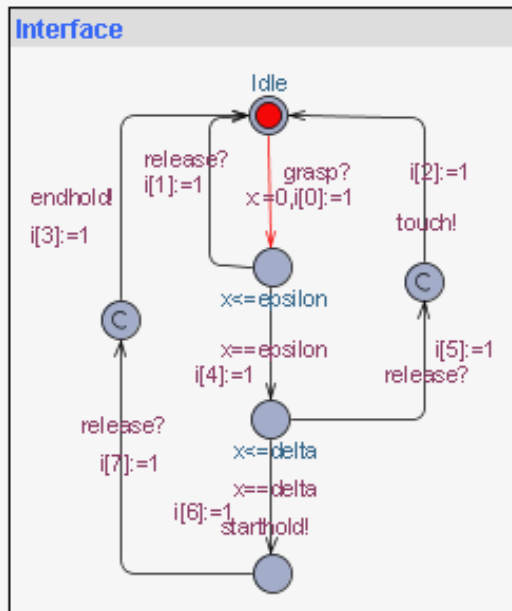
//13
out(IGrasp); // @900 // Bring dimmer PassiveDn->ActiveDN->
silence(500); //hold // ActiveUP+increase to level 10
silence(1000); in(OSetLevel,1);
silence(1000); in(OSetLevel,2);
silence(1000); in(OSetLevel,3);
silence(1000); in(OSetLevel,4);
silence(1000); in(OSetLevel,5);
silence(1000); in(OSetLevel,6);
silence(1000); in(OSetLevel,7);
silence(1000); in(OSetLevel,8);
silence(1000); in(OSetLevel,9);
silence(1000); in(OSetLevel,10)
silence(1000); in(OSetLevel,9); //bring dimm State to ActiveDN
    
```

```

out(IRelease); //check release->grasp is ignored
out(IGrasp); // @12400
out(IRelease);
silence(dFTolerance);
    
```

Page 2

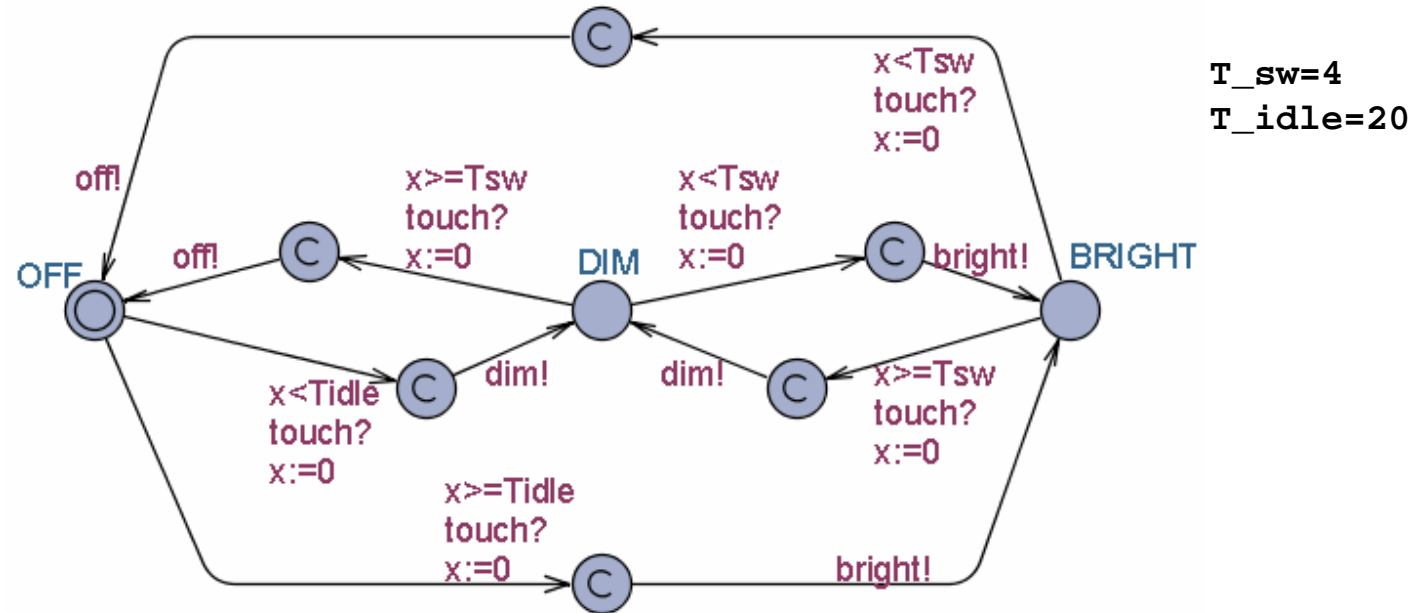
Off-Line Testing = Optimal Reachability



- Specific Test Purposes
- Model Coverage
- Optimal test-suites

Timed Automata

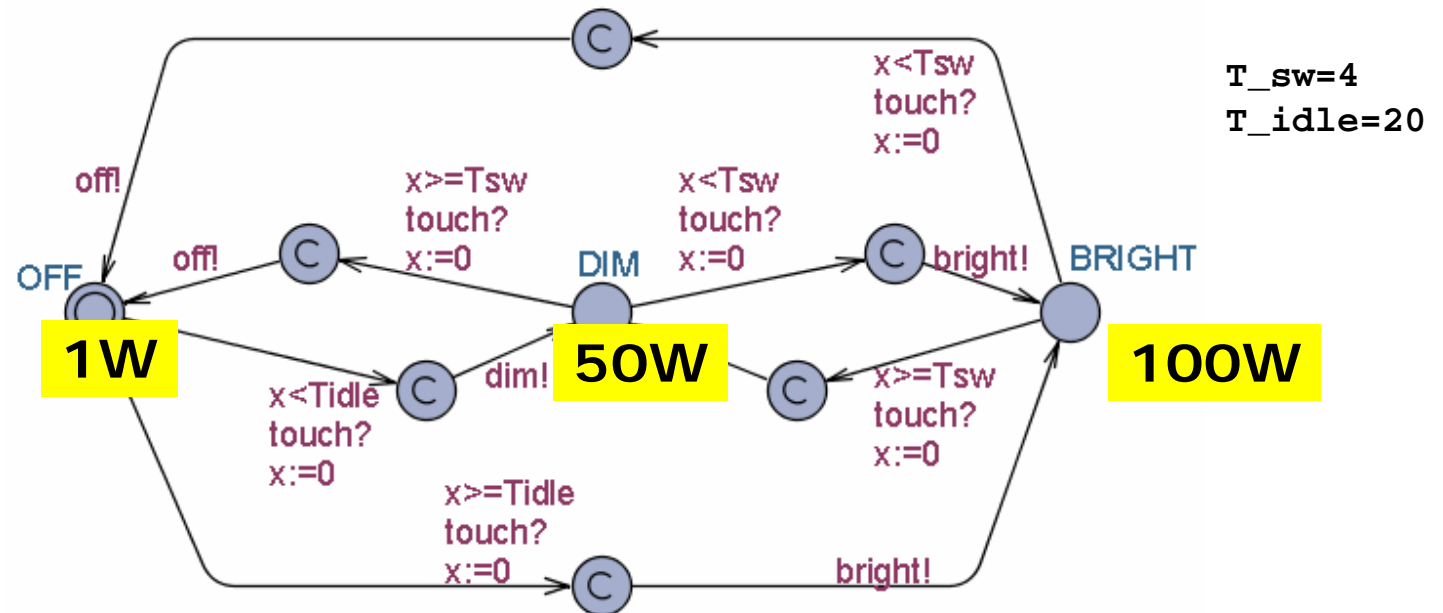
(E)FSM+clocks+guards+resets



WANT: if touch is issued twice **quickly** then the **light** will get **brighter**; otherwise the light is turned **off**.

Solution: Add **real-valued clock** **x**

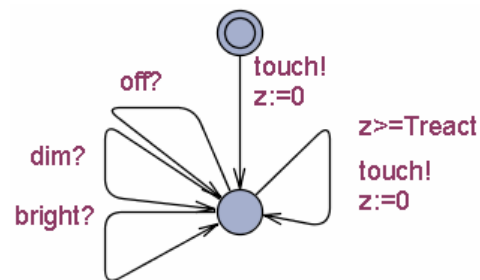
Optimal Tests



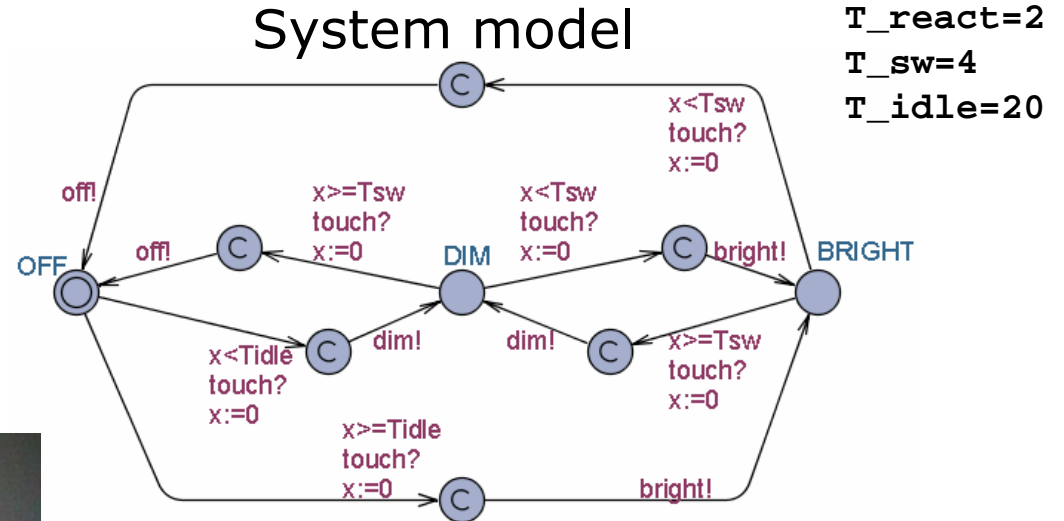
- *Shortest* test for bright light??
- *Fastest* test for bright light??
- *Fastest* edge-covering test suite??
- Least *power* consuming test??

Simple Light Controller

Environment model



System model



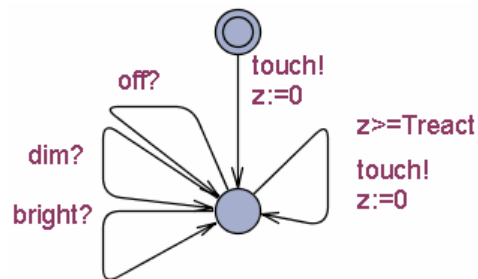
T_react=2
T_sw=4
T_idle=20



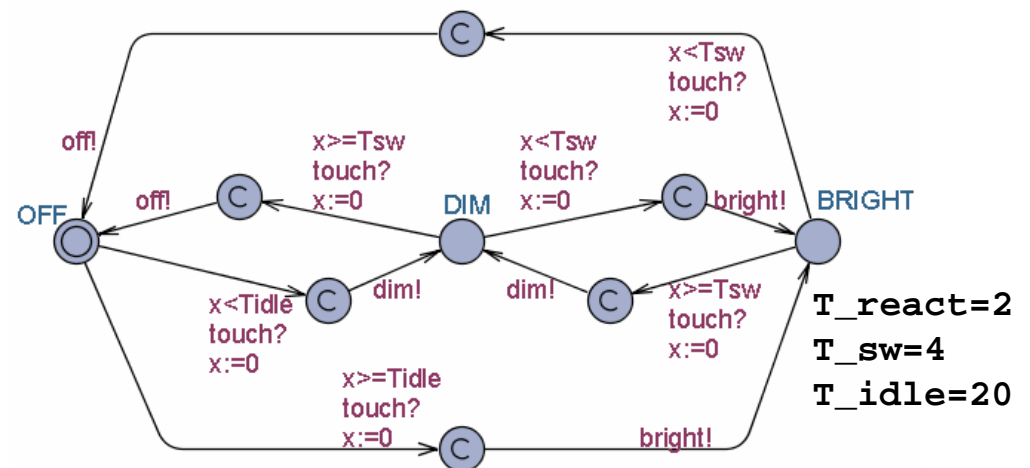
Test Purposes

A specific test objective (or observation) the tester wants to make on SUT

Environment model



System model



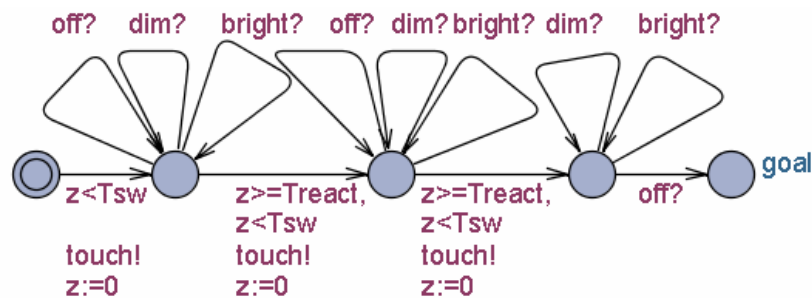
TP1: Check that the light can become bright:

$E \langle \rangle \text{LightController.bright}$

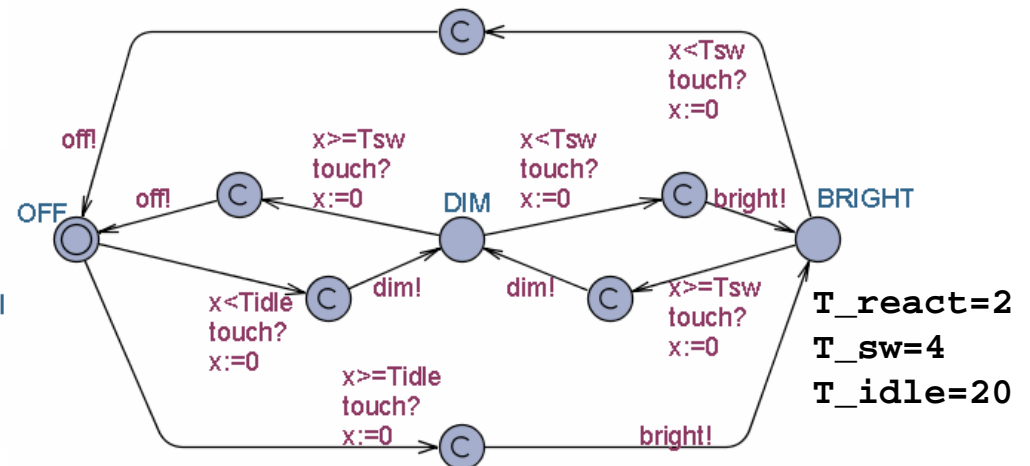
- *Shortest* Test: $20 \cdot \text{touch!} \cdot 0 \cdot \text{bright?} \cdot \text{PASS}$
- *Fastest* Test: $0 \cdot \text{touch!} \cdot 0 \cdot \text{dim?} \cdot 2 \cdot \text{touch!} \cdot 0 \cdot \text{bright?} \cdot \text{PASS}$

Test Purposes 2

Environment model*TP2



System model



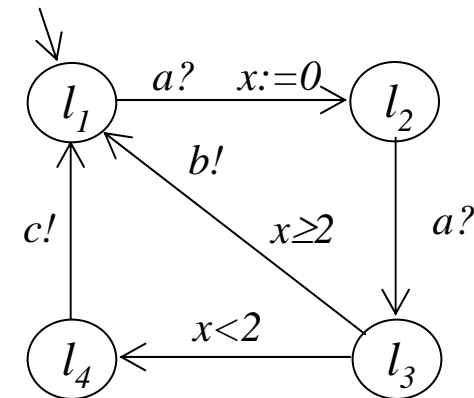
TP2: Check that the light switches off after three successive touches

Use restricted environment and `E<> tpEnv.goal`

- The fastest test sequence is `0·touch!·0·dim?·2·touch!·0·bright?·2·touch!·0·off?·PASS`

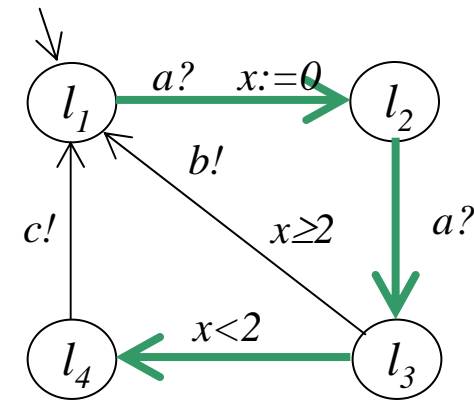
Coverage Based Test Generation

- Multi purpose testing
- Cover measurement
- Examples:
 - Location coverage,
 - Edge coverage,
 - Definition/use pair coverage



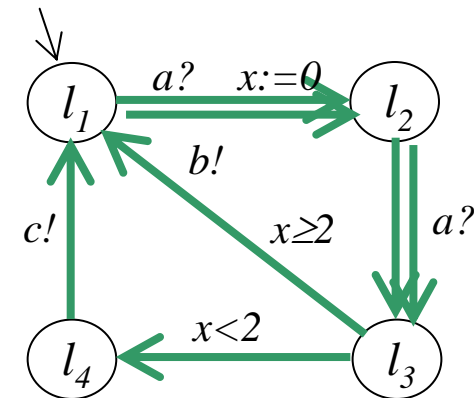
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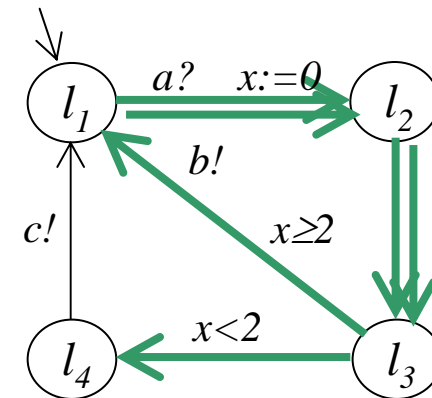
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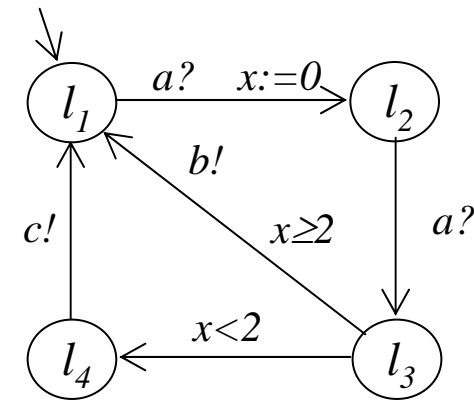
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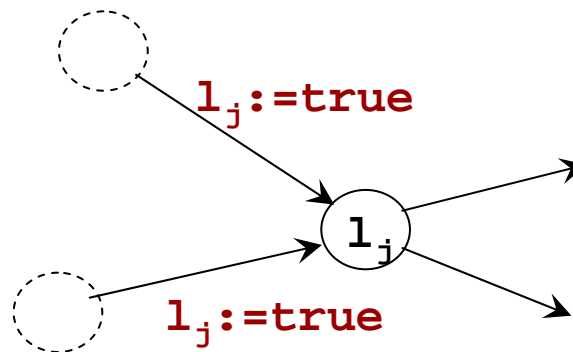
Coverage Based Test Generation

- Multi purpose testing
- Cover measurement
- Examples:
 - Locations coverage,
 - Edge coverage,
 - Definition/use pair coverage
 - All Definition/Use pairs
- Generated by min-cost reachability analysis of annotated graph



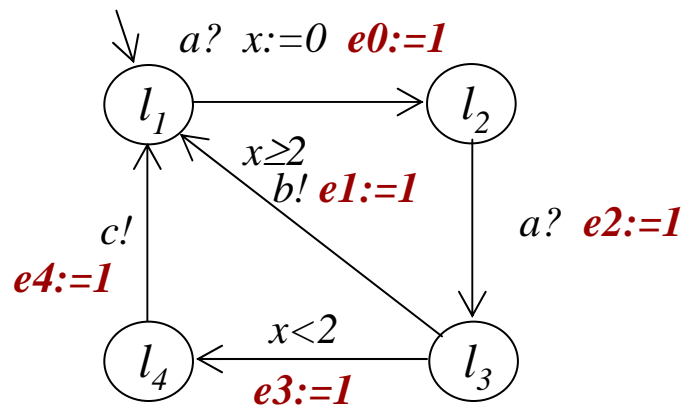
Location Coverage

- Test sequence traversing all locations
- Encoding:
 - Enumerate locations l_0, \dots, l_n
 - Add an auxiliary variable l_i for each location
 - Label each ingoing edge to location i $l_i := \text{true}$
 - Mark initial visited $l_0 := \text{true}$
- Check: **EF**($l_0 = \text{true} \wedge \dots \wedge l_n = \text{true}$)

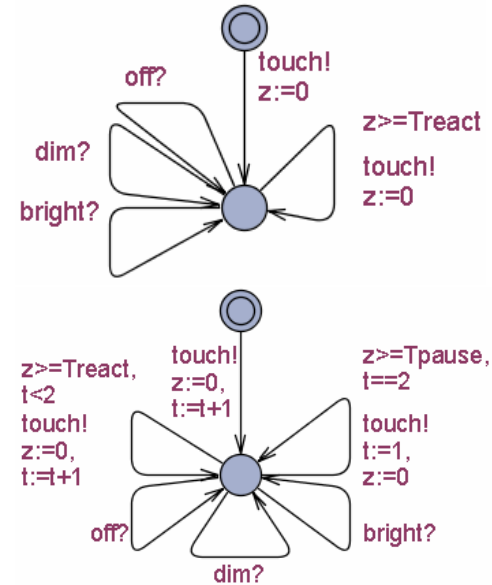
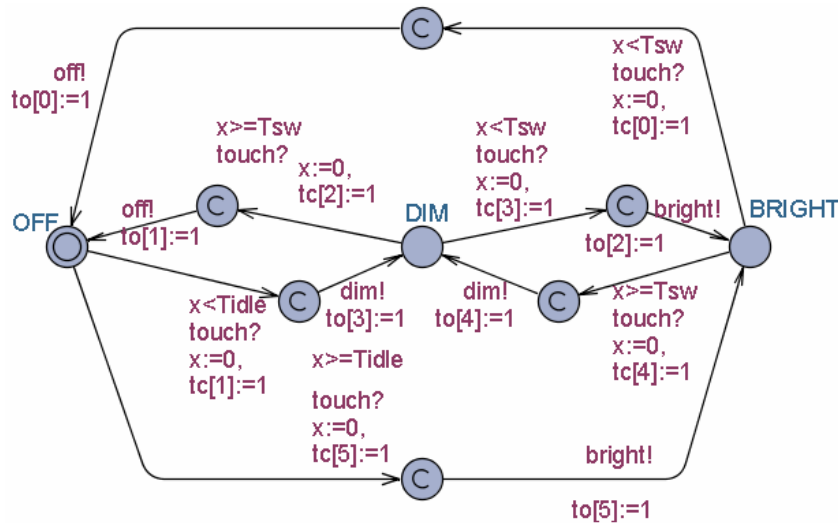


Edge Coverage

- Test sequence traversing all edges
- Encoding:
 - Enumerate edges e_0, \dots, e_n
 - Add auxiliary variable e_i for each edge
 - Label each edge $e_i := \text{true}$
- Check: $\mathbf{EF}(e_0 = \text{true} \wedge \dots \wedge e_n = \text{true})$



Edge Coverage



EC: $T_{react}=0$

0·touch!·0·dim?·0·touch!·0·bright?·0·touch!·0·off?·
20·touch!·0·bright?·4·touch!·0·dim?·4·touch!·0·off?·PASS

Time=28

EC': $T_{react}=2$

0·touch!·0·dim?·4·touch!·0·off?· 20·touch!·0·bright?·
4·touch!·0·dim?·2·touch!·0·bright?·2·touch!·0·off?·PASS

Time=32

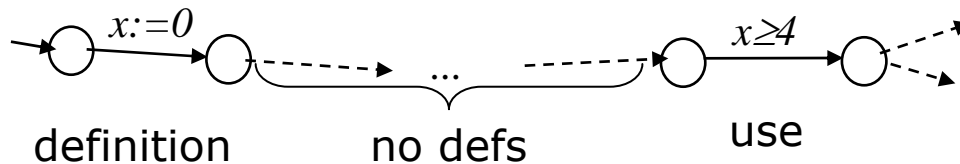
EC'': *pausing user* $T_{react}=2, T_{pause}=5$

0·touch!·0·dim?·2·touch!·0·bright?·5·touch!·0·dim?·
4·touch!·0·off?·20·touch!·0·bright?·2·touch!·0·off?·PASS

Time=33

Definition/Use Pair Coverage

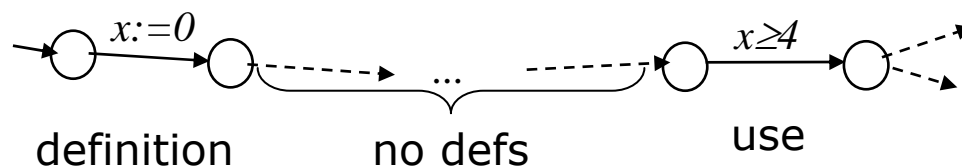
- Dataflow coverage technique
- Def/use pair of variable x :



- Encoding:
 - $v_d \in \{false\} \cup \{e_0, \dots, e_n\}$, initially false
 - Boolean array du of size $|E| \times |E|$
 - At definition on edge i : $v_d := e_i$
 - At use on edge j : $if(v_d) then du[v_d, e_j] := true$

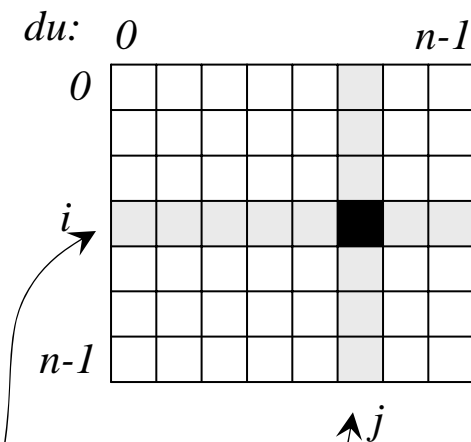
Definition/Use Pair Coverage

- Dataflow coverage technique
- Def/use pair of variable x :



- Encoding:

- $v_d \in \{false\} \cup \{e_0, \dots, e_n\}$, initially false
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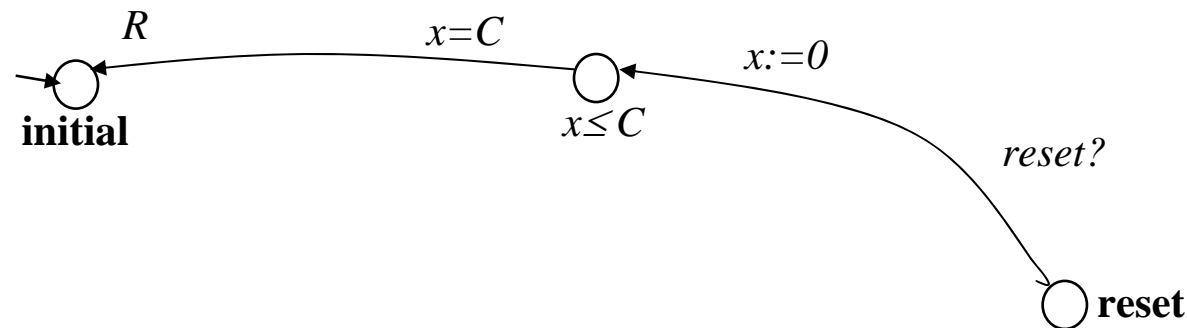


- Check:

- $\text{EF}(\text{ all } du[i,j] = true)$

Test Suite Generation

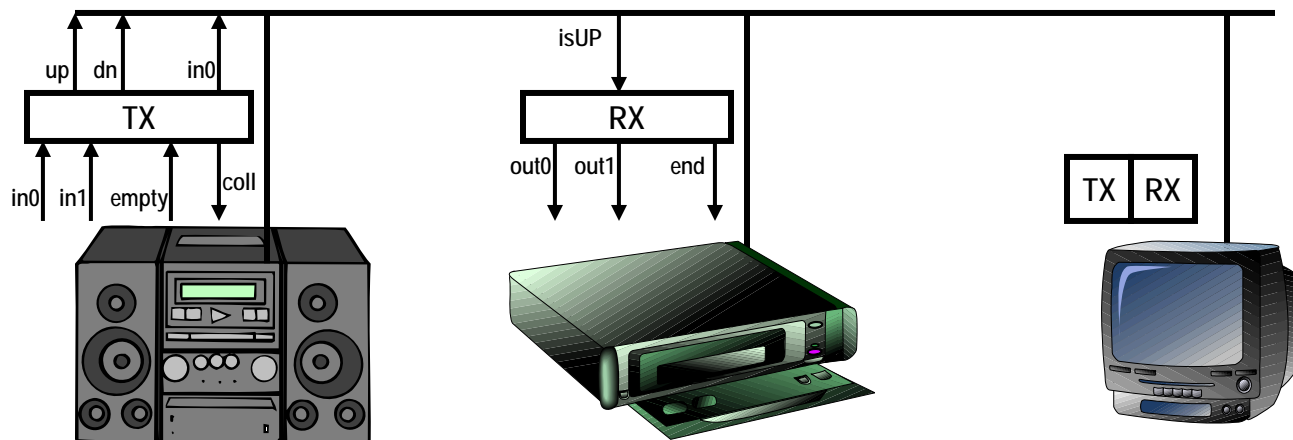
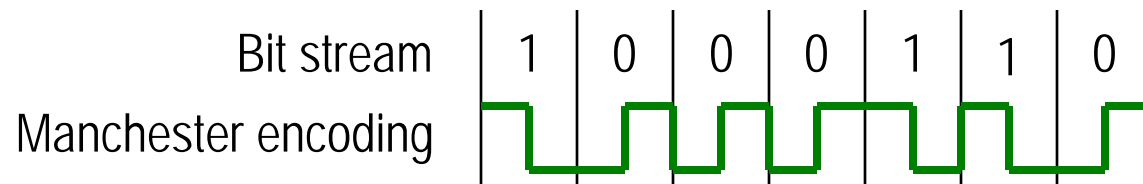
- In general a set of test cases is needed to cover a test criteria
- Add global reset of SUT and environment model and associate a cost (of system reset)



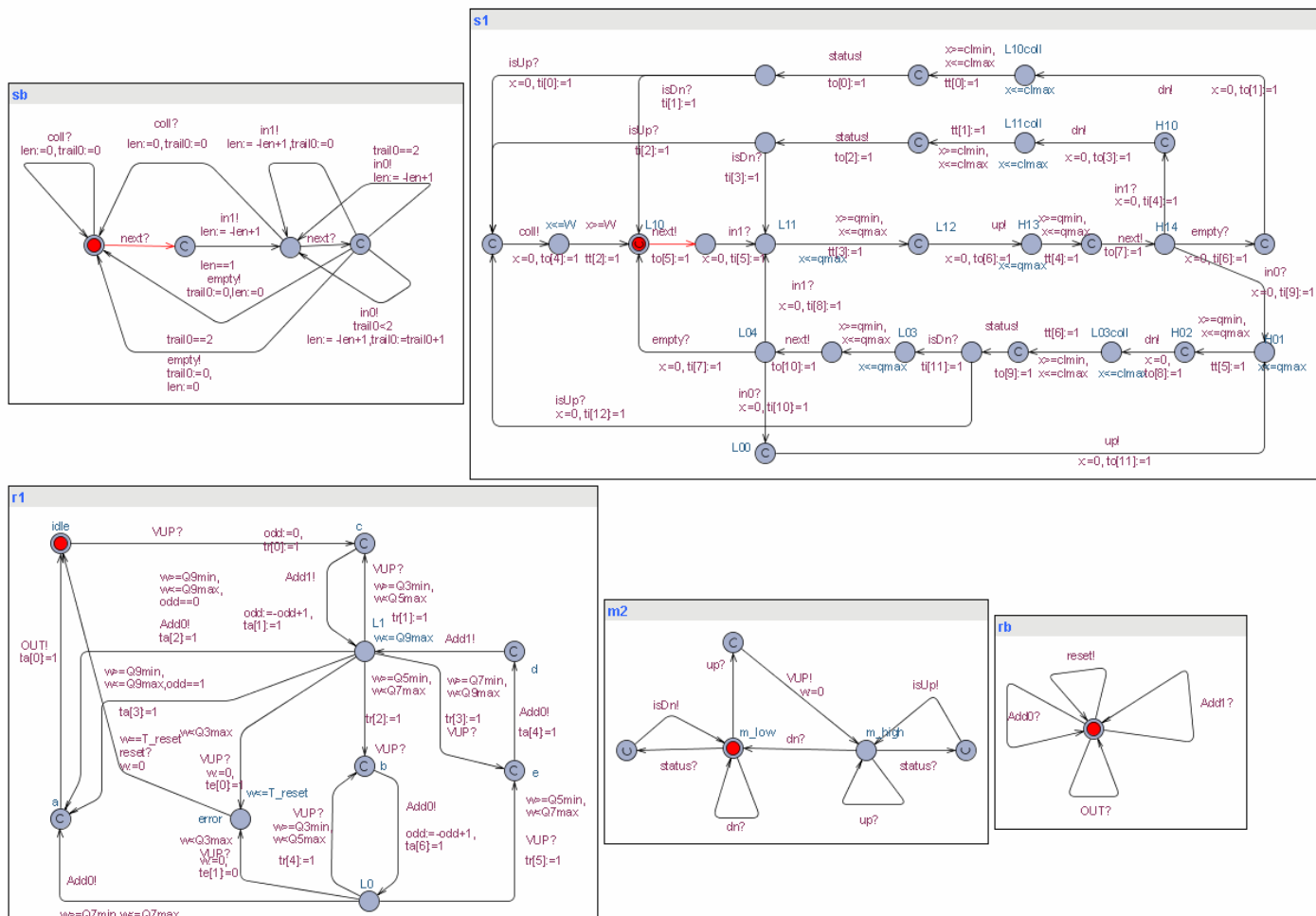
- Same encodings and min-cost reachability
- Test sequence $\sigma = \mathcal{E}_0, i_0, \dots, \mathcal{E}_1, i_1, \underbrace{\text{reset } \mathcal{E}_2, i_2, \dots, \mathcal{E}_0, i_0, \text{reset}, \mathcal{E}_1, i_1, \mathcal{E}_2, i_2, \dots}_{\sigma_i}$
- Test suite $T = \{ \sigma_1, \dots, \sigma_n \}$ with minimum cost

The Philips Audio Protocol

- A bus based protocol for exchanging control messages between audio components
 - Collisions
 - Tolerance on timing events



Philips Audio Protocol



Benchmark Example

- Philips Audio Protocol

Coverage Criterion	Execution time (μ s)	Generation time (s)	Memory usage (KB)
Edge _{Sender}	212350	2.2	9416
Edge _{Receiver}	18981	1.2	4984
Edge _{Sender, Bus, Receiver}	114227	129.0	331408

Off-Line Test Generation

*Observable
Timed Automata*



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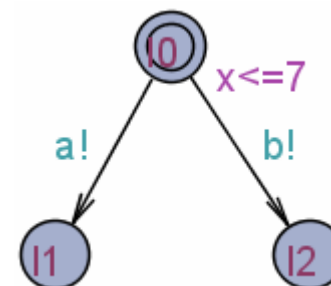
Basic Research
in Computer Science



CENTER FOR INDLEJREDE SOFTWARE SYSTEMER

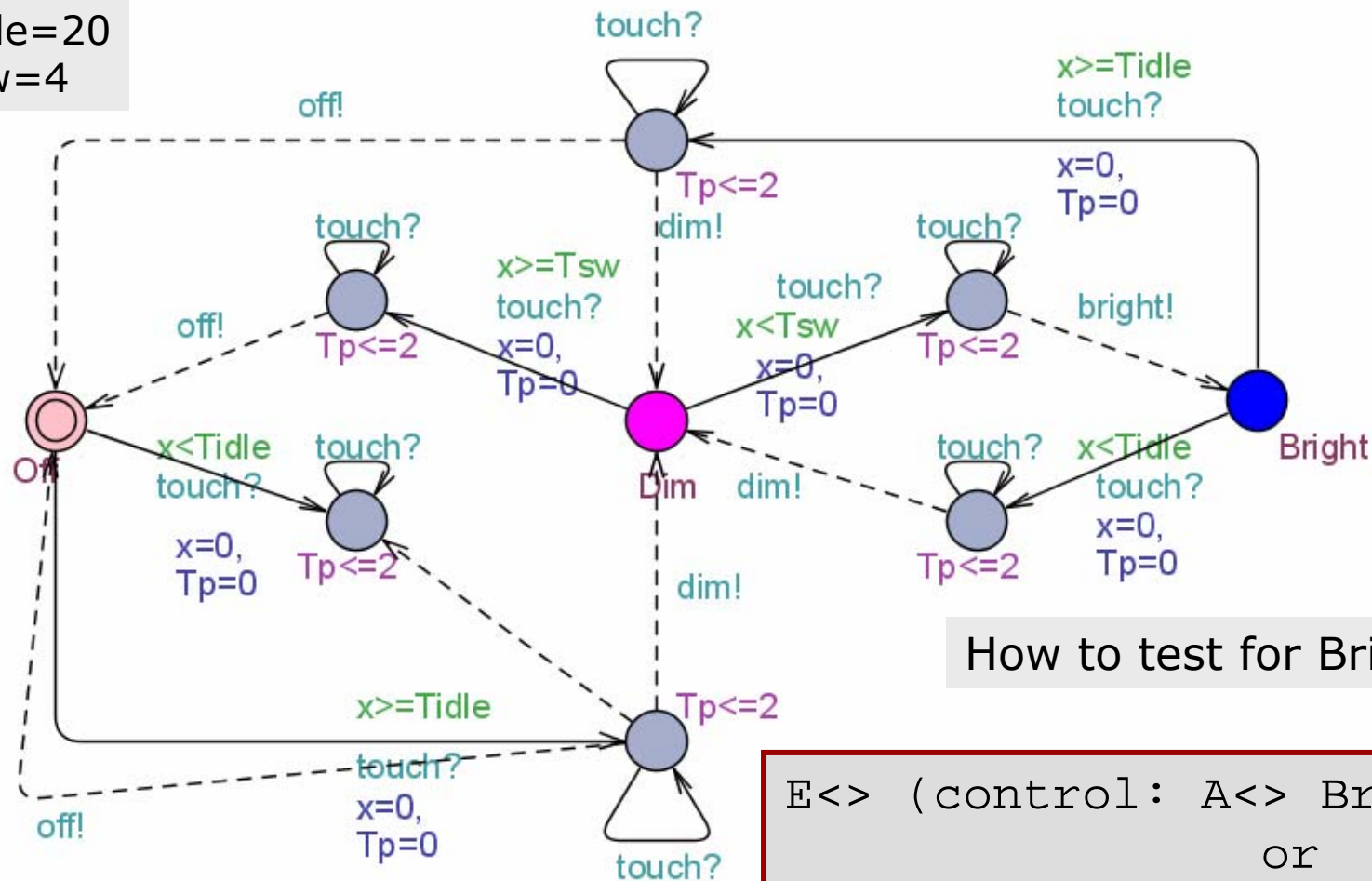
Observable Timed Automata

- **Determinism:**
two transitions with same input/output leads to the same state
- **Input Enabled:**
all inputs can always be accepted
- **Time Uncertainty of outputs:**
timing of outputs uncontrollable by tester
- **Uncontrollable output:**
IUT controls which enabled output will occur in what order



A trick light control

Tidle=20
Tsw=4



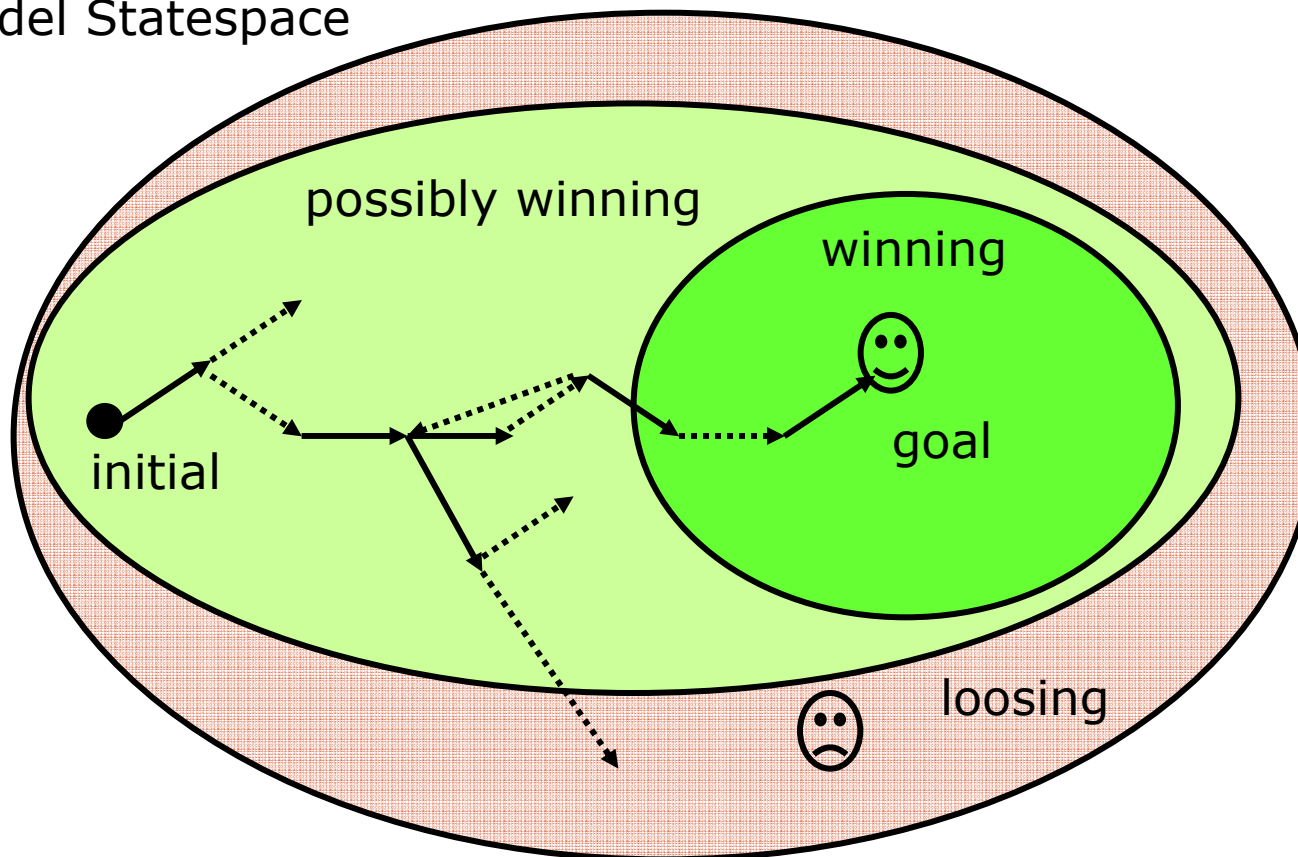
How to test for Bright ?

```

E<> (control: A<> Bright)
      or
<<c,u>> ◇ (<<c>> ◇ Bright)
    
```

Cooperative Strategies

Model Statespace



- Play the game (execute test) while time available or game is lost
- Possibly using randomized online testing

On-Line Testing

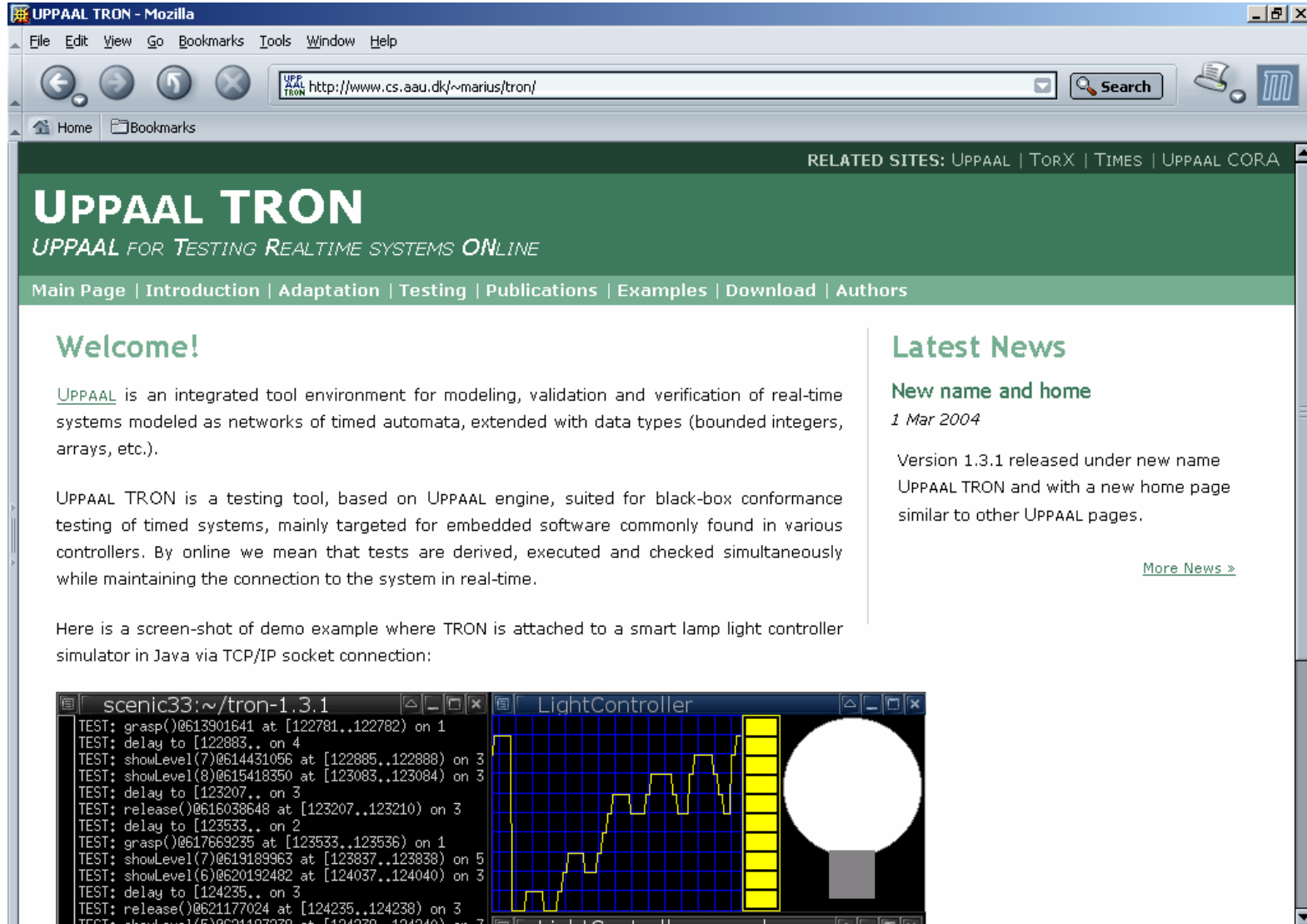


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UPPAAL TRON - Mozilla

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UPPAAL TRON

UPPAAL FOR TESTING REALTIME SYSTEMS ONLINE

Main Page | Introduction | Adaptation | Testing | Publications | Examples | Download | Authors

Welcome!

UPPAAL is an integrated tool environment for modeling, validation and verification of real-time systems modeled as networks of timed automata, extended with data types (bounded integers, arrays, etc.).

UPPAAL TRON is a testing tool, based on UPPAAL engine, suited for black-box conformance testing of timed systems, mainly targeted for embedded software commonly found in various controllers. By online we mean that tests are derived, executed and checked simultaneously while maintaining the connection to the system in real-time.

Here is a screen-shot of demo example where TRON is attached to a smart lamp light controller simulator in Java via TCP/IP socket connection:

Latest News

New name and home

1 Mar 2004

Version 1.3.1 released under new name UPPAAL TRON and with a new home page similar to other UPPAAL pages.

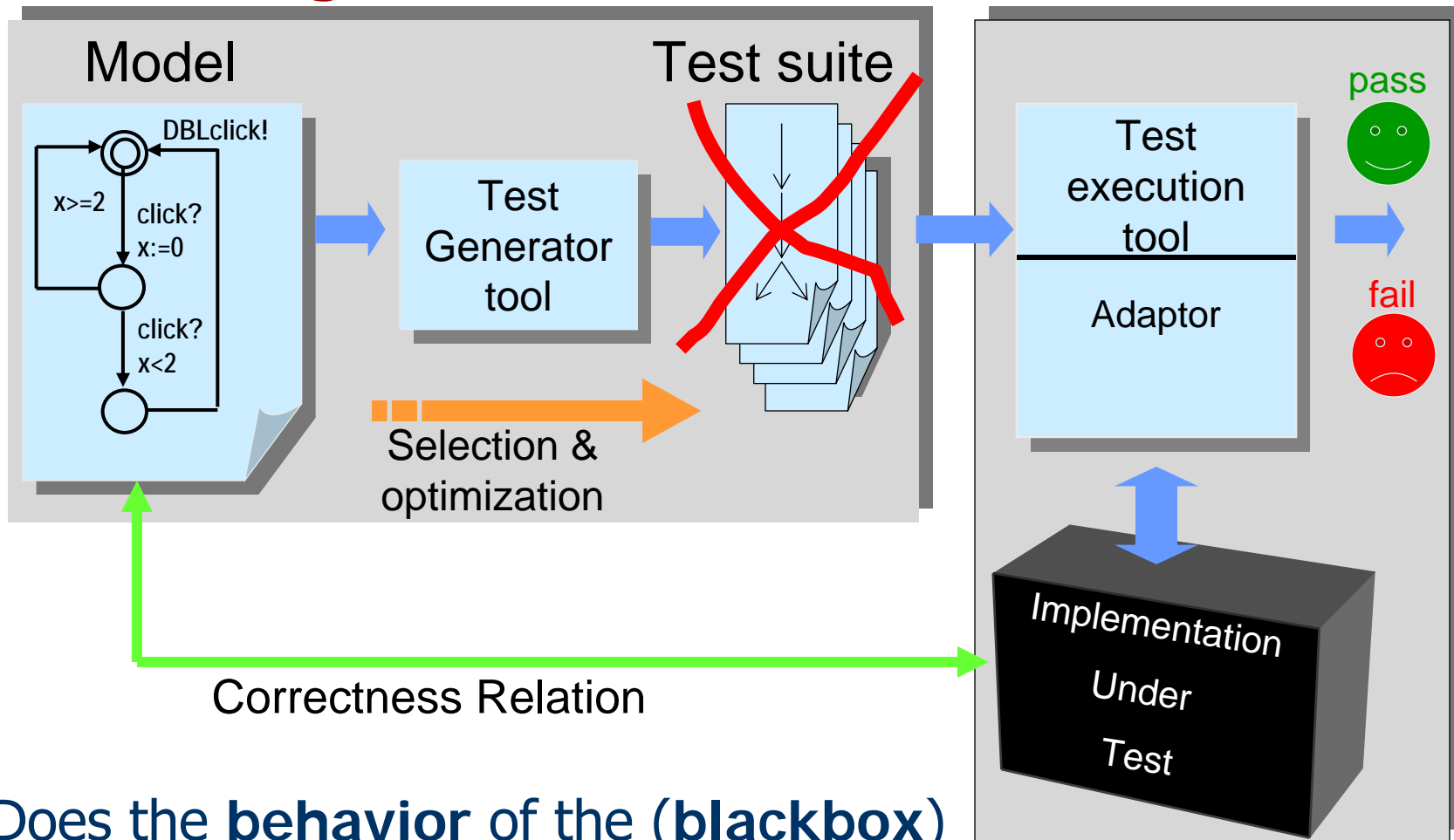
[More News >](#)

```

scenic33:~/tron-1.3.1
TEST: grasp()@613901641 at [122781..122782) on 1
TEST: delay to [122883.. on 4
TEST: showLevel(7)@614431056 at [122885..122888) on 3
TEST: showLevel(8)@615418350 at [123083..123084) on 3
TEST: delay to [123207.. on 3
TEST: release()@616038648 at [123207..123210) on 3
TEST: delay to [123533.. on 2
TEST: grasp()@617669235 at [123533..123536) on 1
TEST: showLevel(7)@619189963 at [123837..123838) on 5
TEST: showLevel(6)@620192482 at [124037..124040) on 3
TEST: delay to [124235.. on 3
TEST: release()@621177024 at [124235..124238) on 3
TEST: showLevel(5)@621197239 at [124239..124240) on 7
  
```

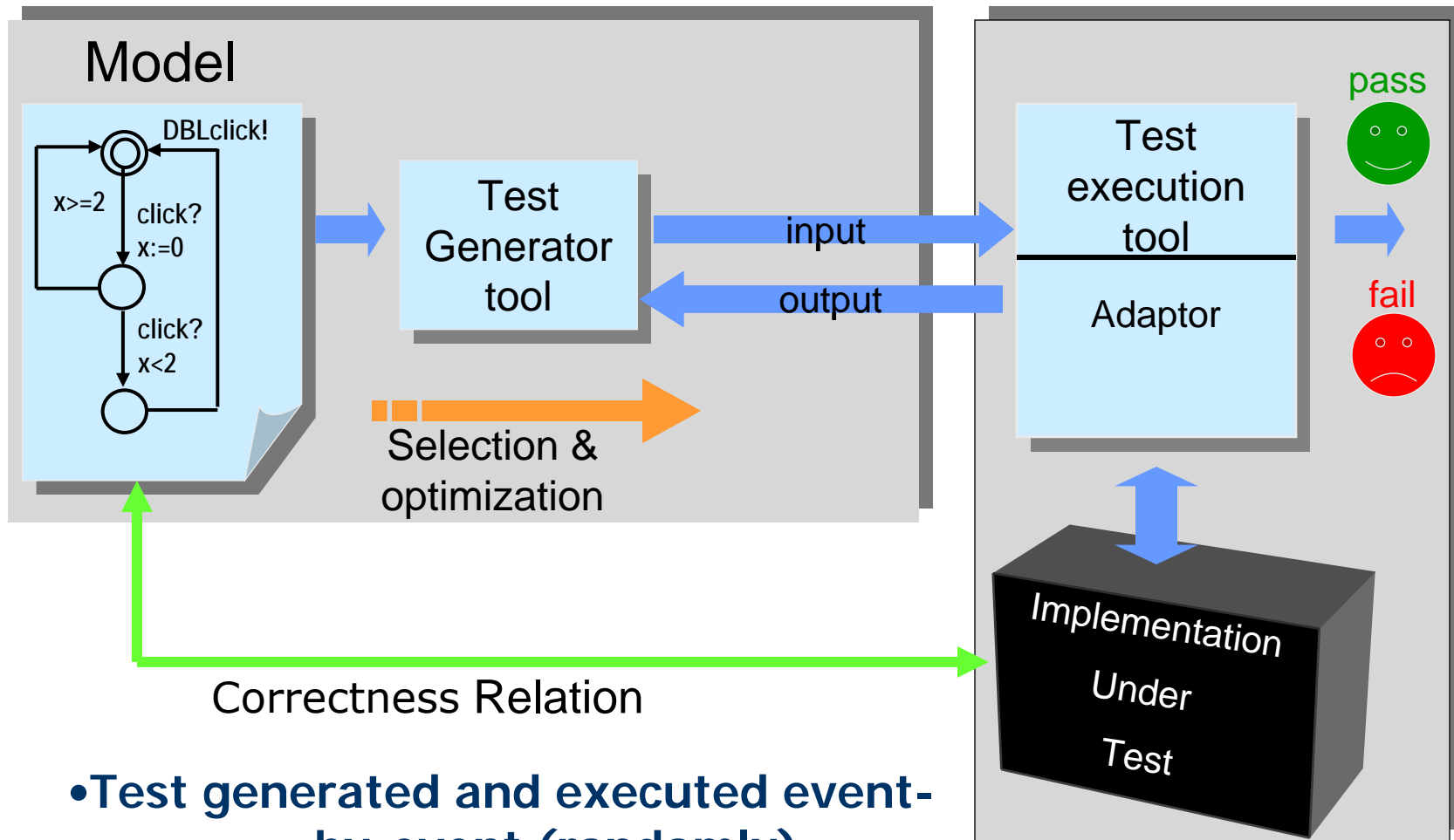
LightController

Automated Model Based Conformance Testing



Does the **behavior** of the (**blackbox**) implementation *comply* to that of the specification?

Online Testing



- Test generated and executed event-by-event (randomly)

• A.K.A on-the-fly testing

An Algorithm



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Basic Research
in Computer Science



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Algorithm Idea:

State-set tracking

- Dynamically compute all potential states that the model M can reach after the timed trace

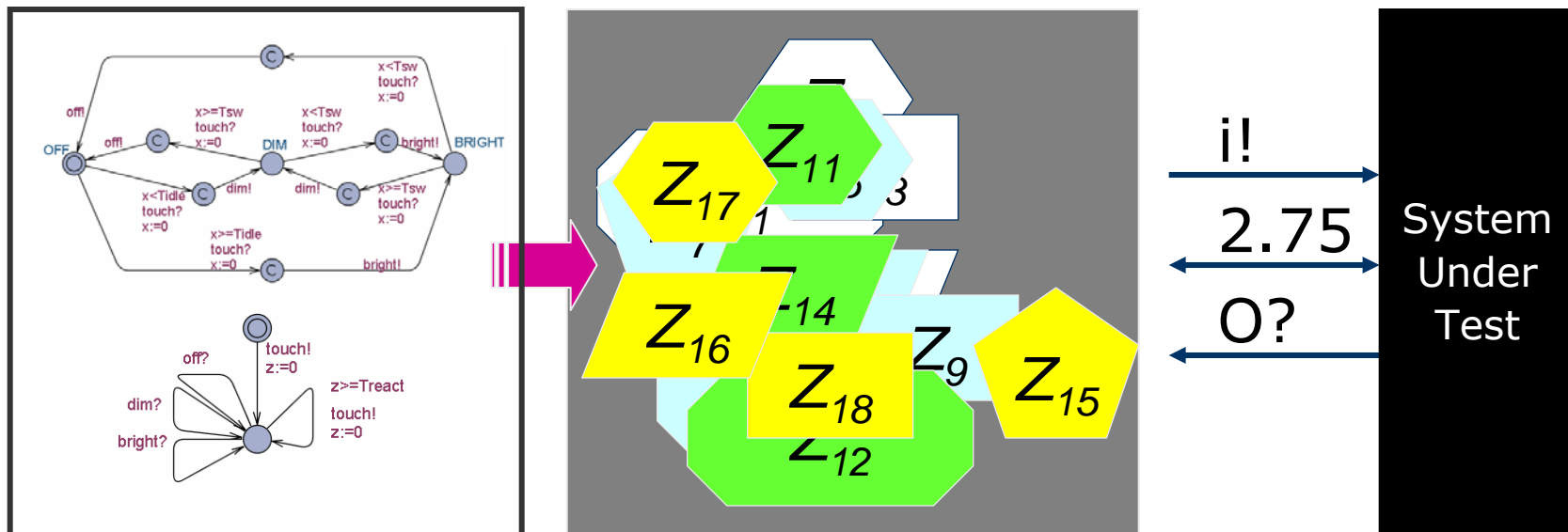
$\varepsilon_0, i_0, \varepsilon_1, o_1, \varepsilon_2, i_2, o_2, \dots$ [Tripakis] Failure Diagnosis

- $Z = M$ **after** $(\varepsilon_0, i_0, \varepsilon_1, o_1, \varepsilon_2, i_2, o_2)$
- If $Z = \emptyset$ the IUT has made a computation not in model:
FAIL
- i is a relevant input in Env iff $I \in EnvOutput(Z)$

Online State Estimation

Timed Automata
Specification

State-set explorer:
maintain and analyse a set of *symbolic* states in real time!



(Abstract) Online Algorithm

Algorithm *TestGenExe* (S, E, IUT, T) returns {**pass**, **fail**)
 $Z := \{(s_0, e_0)\}$.

while $Z \neq \emptyset$ **and** #iterations $\leq T$ **do either** randomly:

1. // offer an input

if $EnvOutput(Z) \neq \emptyset$

 randomly choose $i \in EnvOutput(Z)$

send i to IUT

$Z := Z$ After i

2. // wait d for an output

 randomly choose $d \in Delays(Z)$

wait (for d time units or output o at $d' \leq d$)

if o occurred **then**

$Z := Z$ After d'

$Z := Z$ After o // may become \emptyset (\Rightarrow fail)

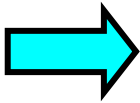
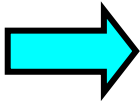
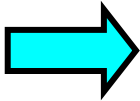
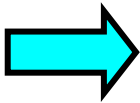
else

$Z := Z$ After d // no output within d delay

3. *restart*:

$Z := \{(s_0, e_0)\}$, **reset** IUT //reset and restart

if $Z = \emptyset$ **then return** **fail** **else return** **pass**



(Abstract) Online Algorithm

Algorithm *TestGenExe* (S, E, IUT, T) returns {**pass**, **fail**)
 $Z := \{(s_0, e_0)\}$.

while $Z \neq \emptyset \square \#iterations \leq T$ **do either** randomly:

1. // offer an input

if $EnvOutput(Z) \neq \emptyset$

randomly choose $i \in EnvOutput(Z)$

send i to IUT

$Z := Z$

2. // wait d for output

randomly choose d

wait (for d)

if o occurred

$Z := Z$

$Z := Z$ After o // may become \emptyset (\Rightarrow fail)

else

$Z := Z$ After d // no output within d delay

3. *restart*:

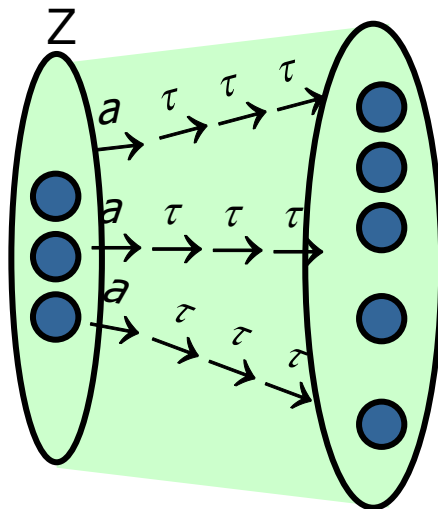
$Z := \{(s_0, e_0)\}$, **reset** IUT //reset and restart

if $Z = \emptyset$ **then return** **fail** **else return** **pass**

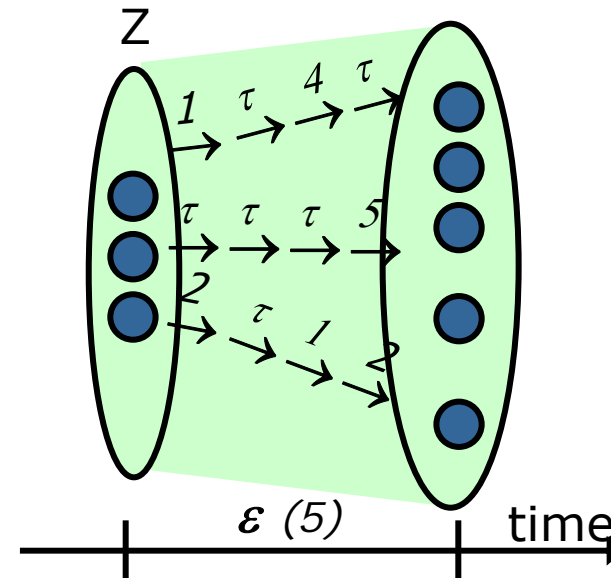
• Sound
 • Complete (as $T \rightarrow \infty$)
 (Under some technical assumptions)

State-set Operations

Z after **a**: possible states
after **action a** (and τ^*)

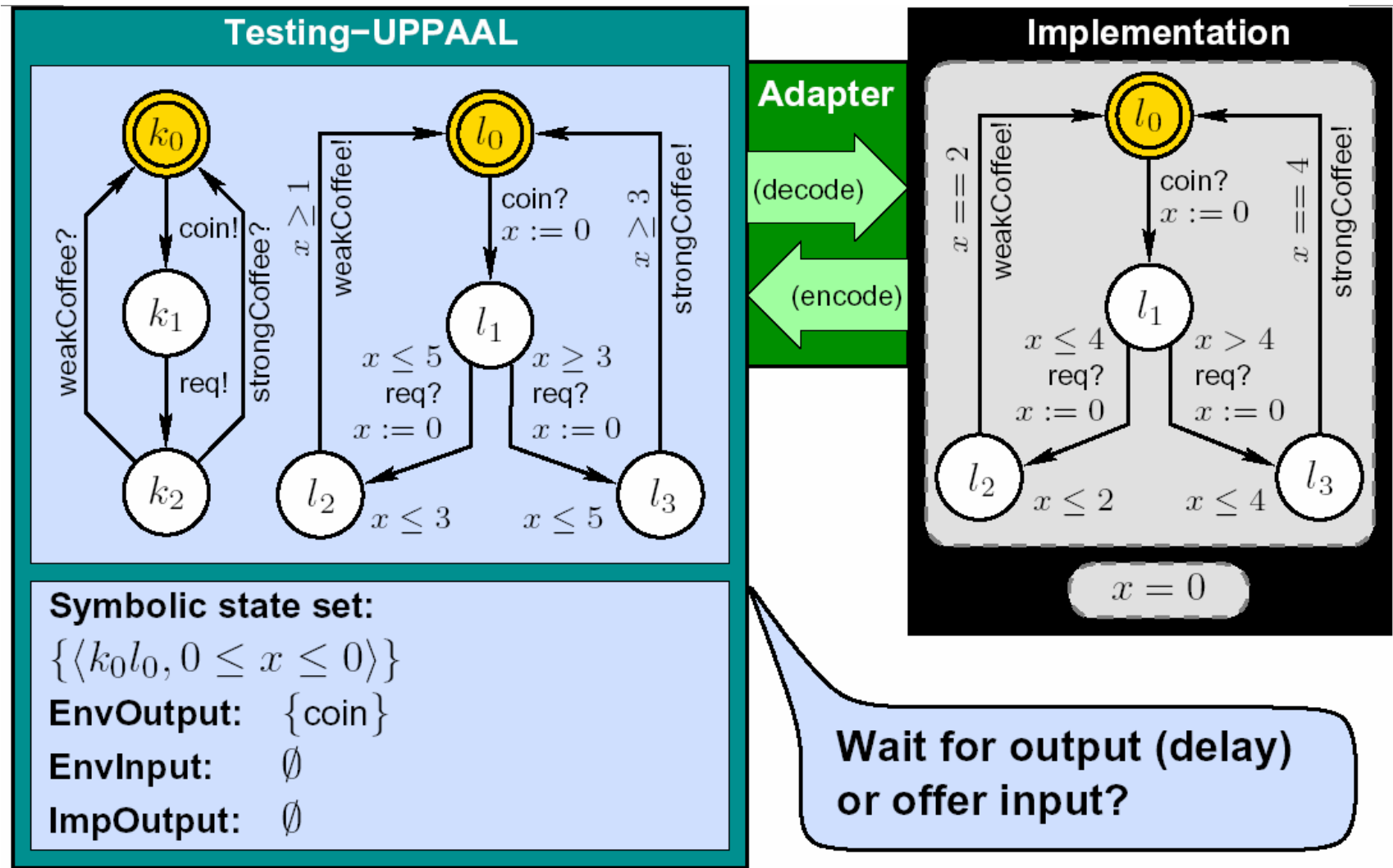


Z after ε : possible states
after τ^* and ε_i , totaling a **delay** of ε

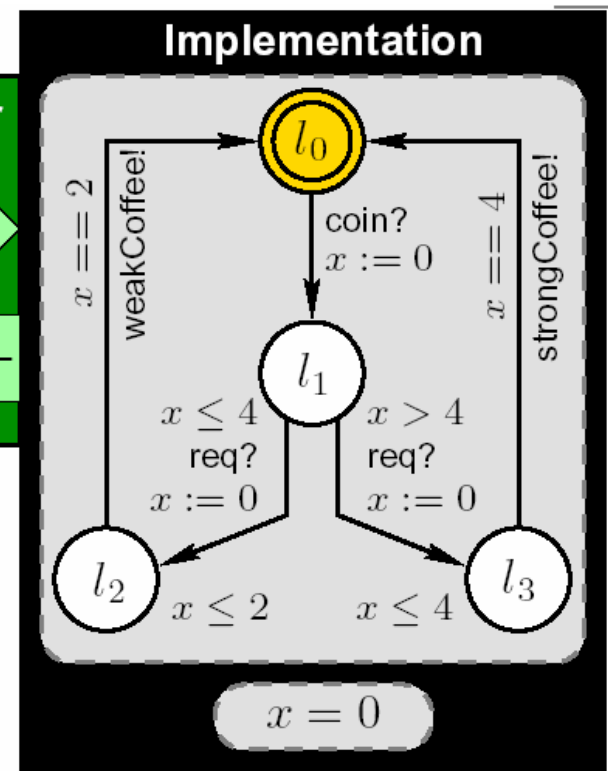
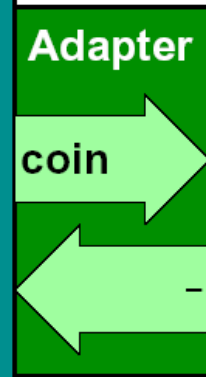
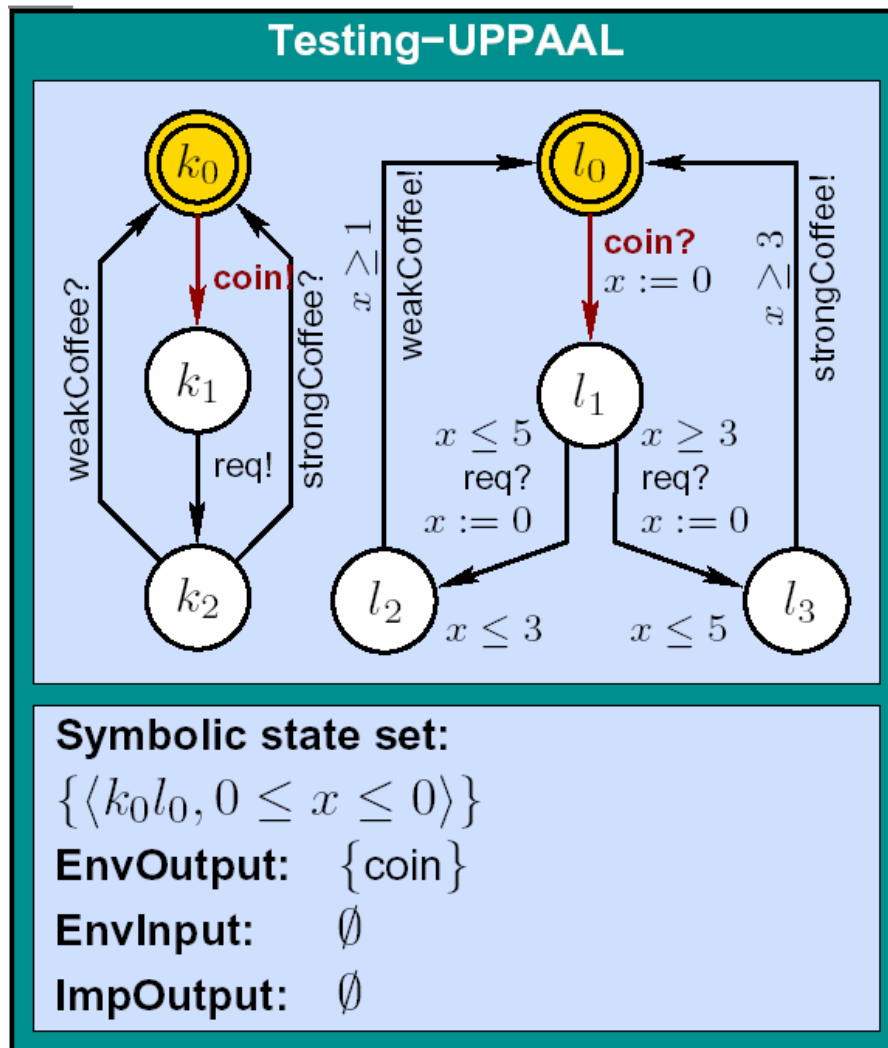


- Can be computed efficiently using the symbolic data structures and algorithms in Uppaal

Online Testing Example

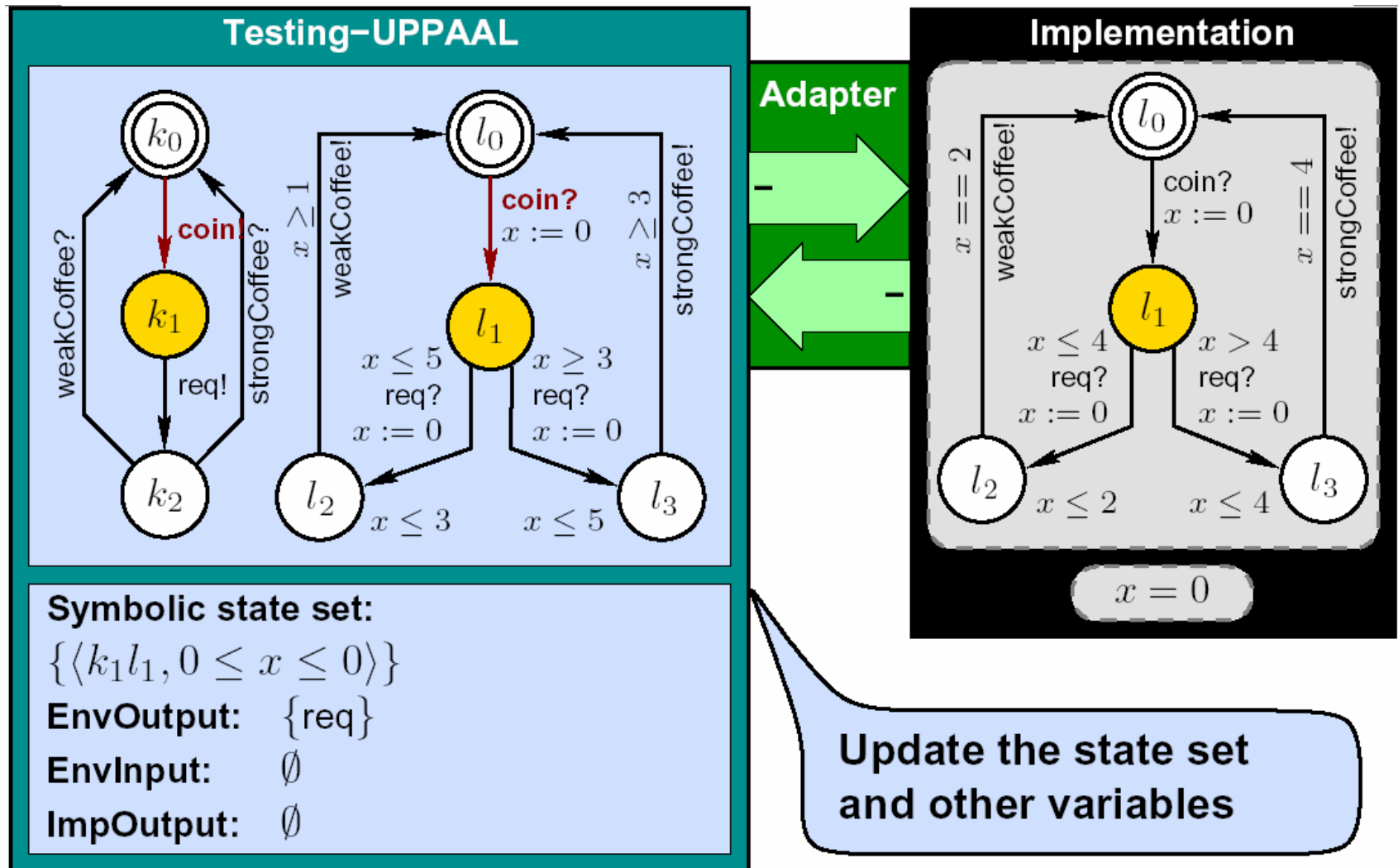


Online Testing

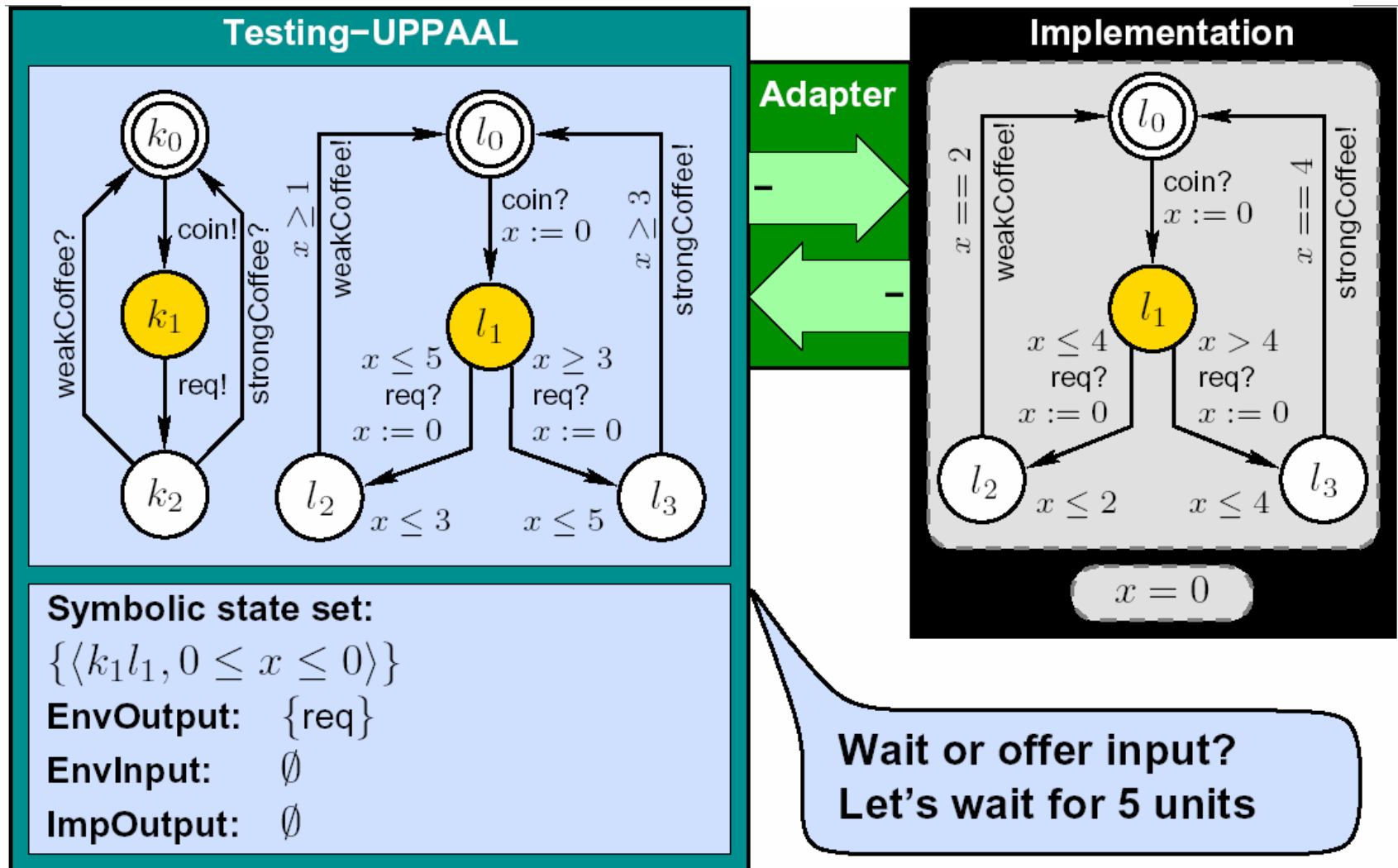


Let's offer input
choose (the only) "coin"

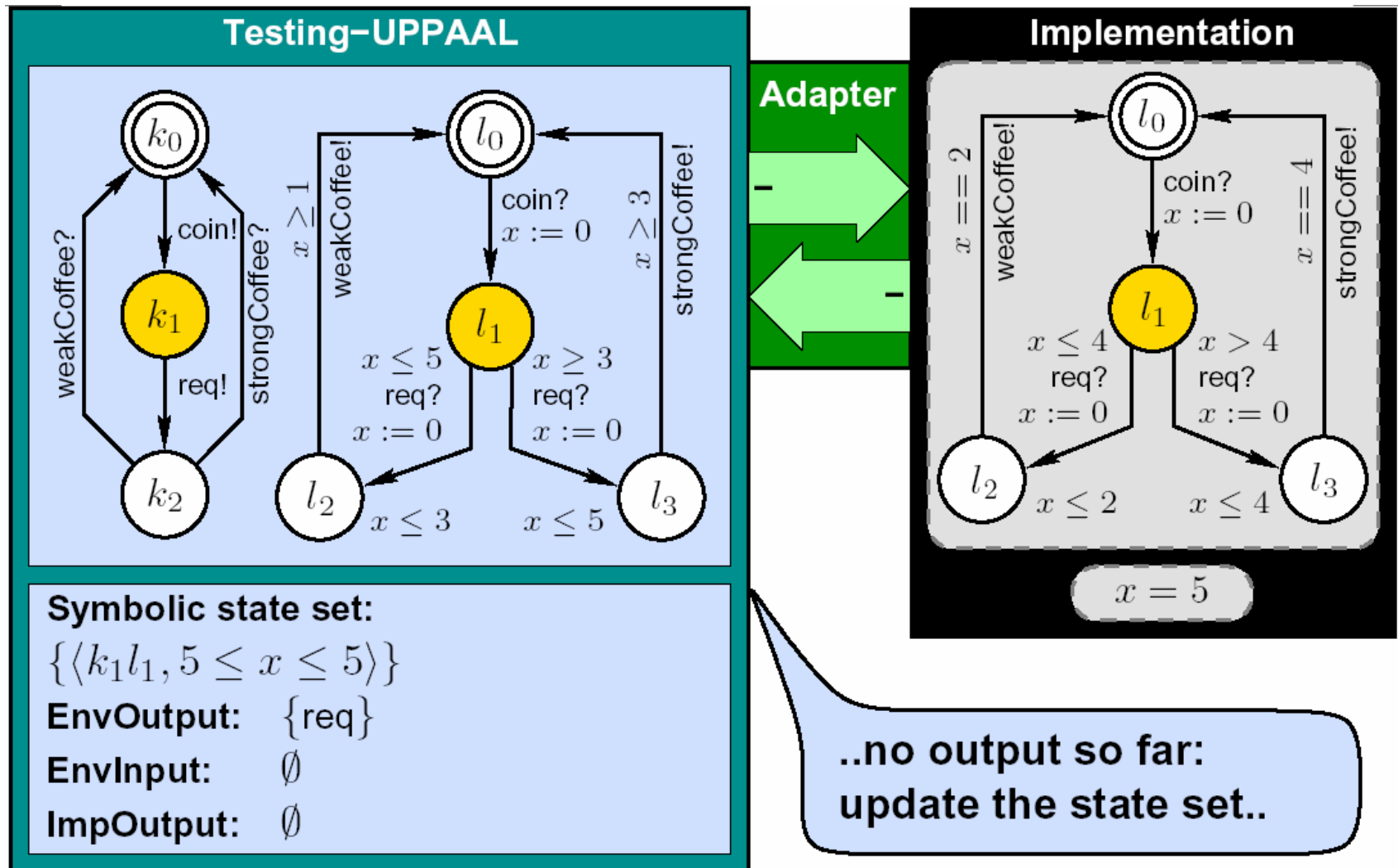
Online Testing



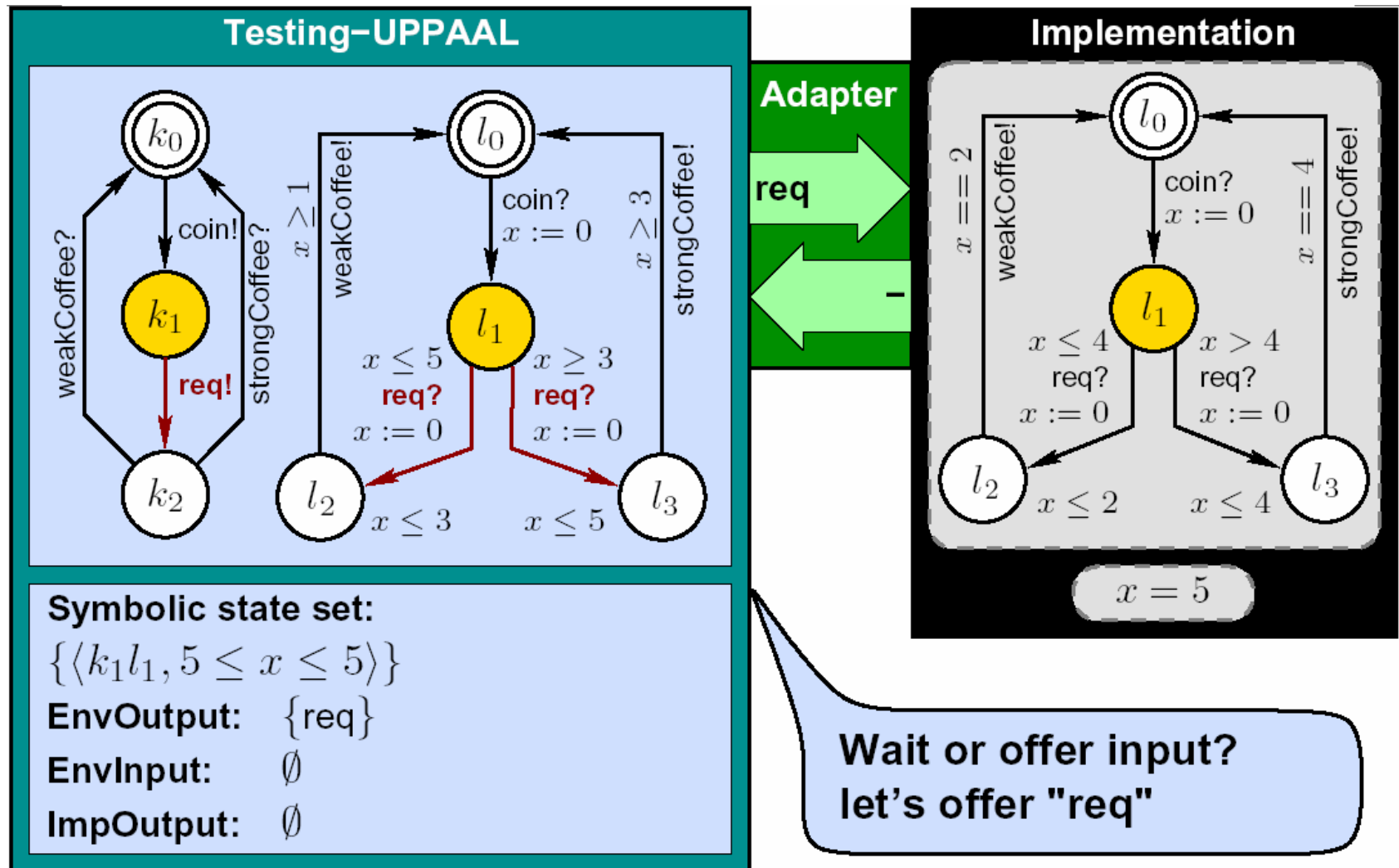
Online Testing



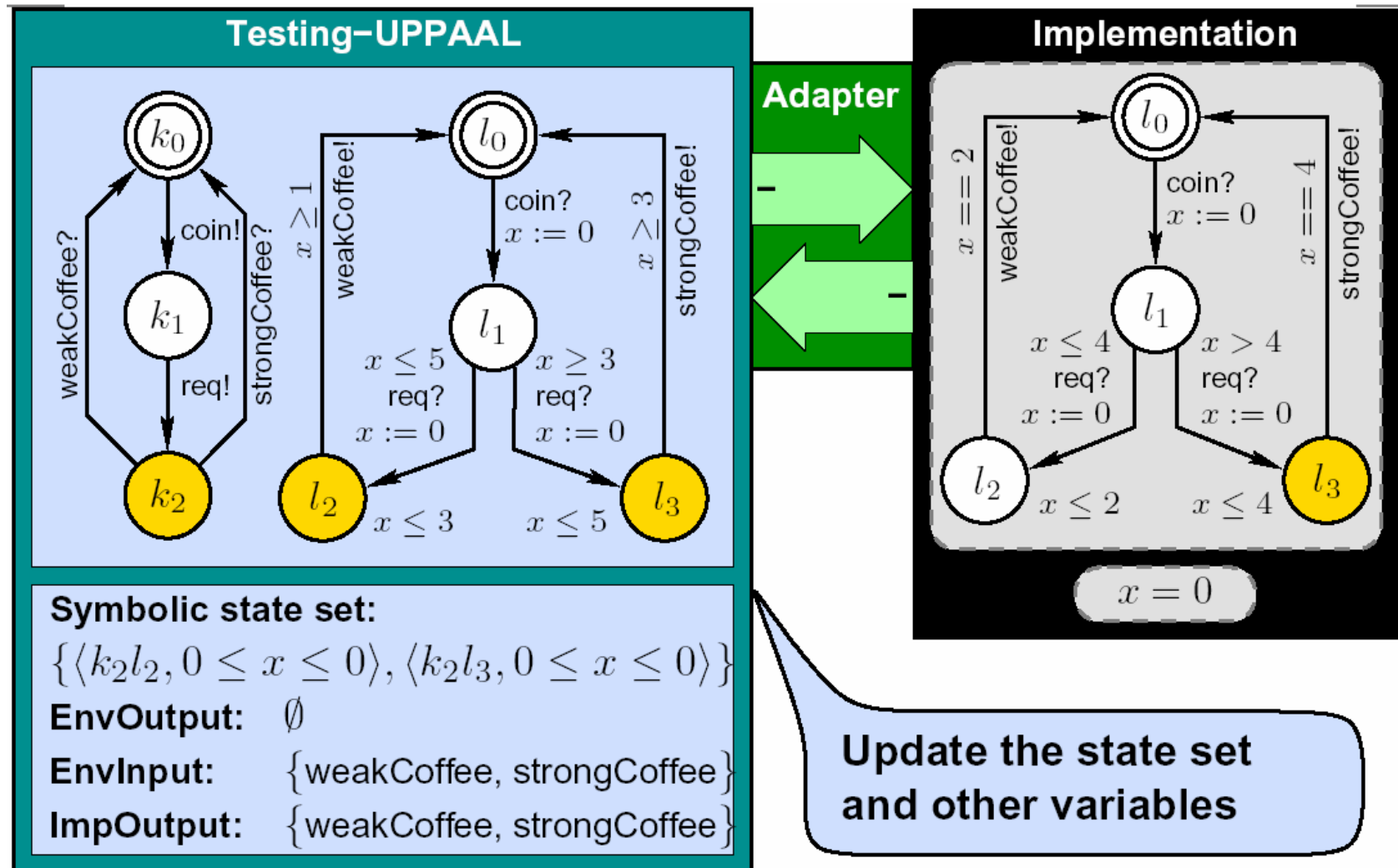
Online Testing



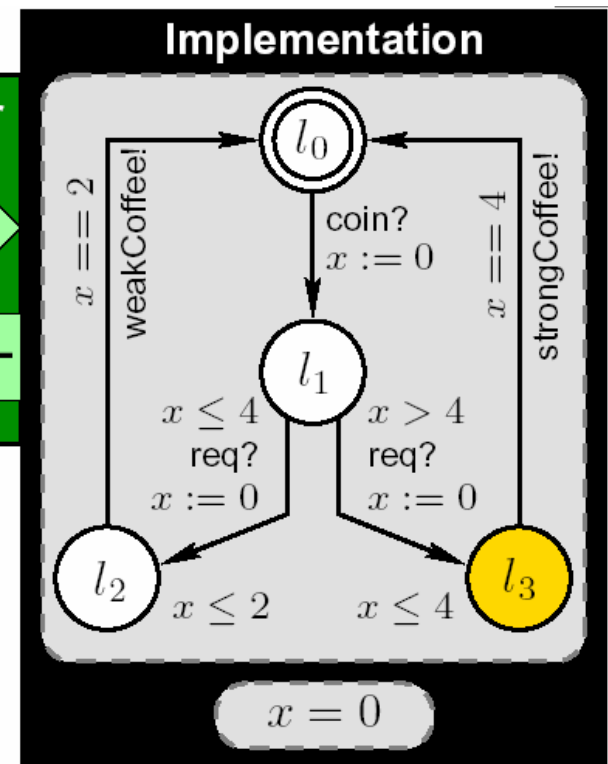
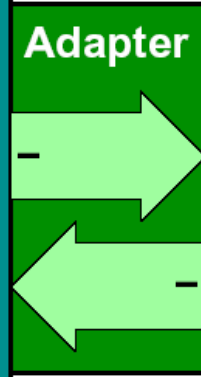
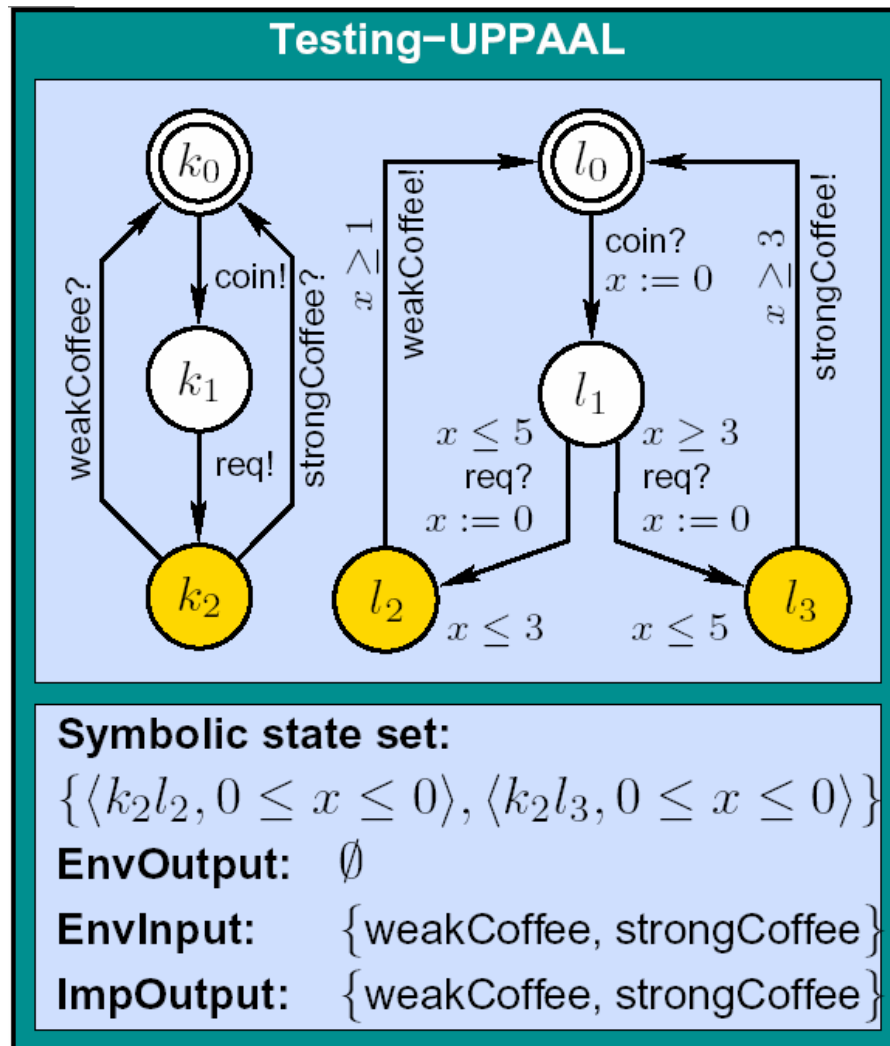
Online Testing



Online Testing

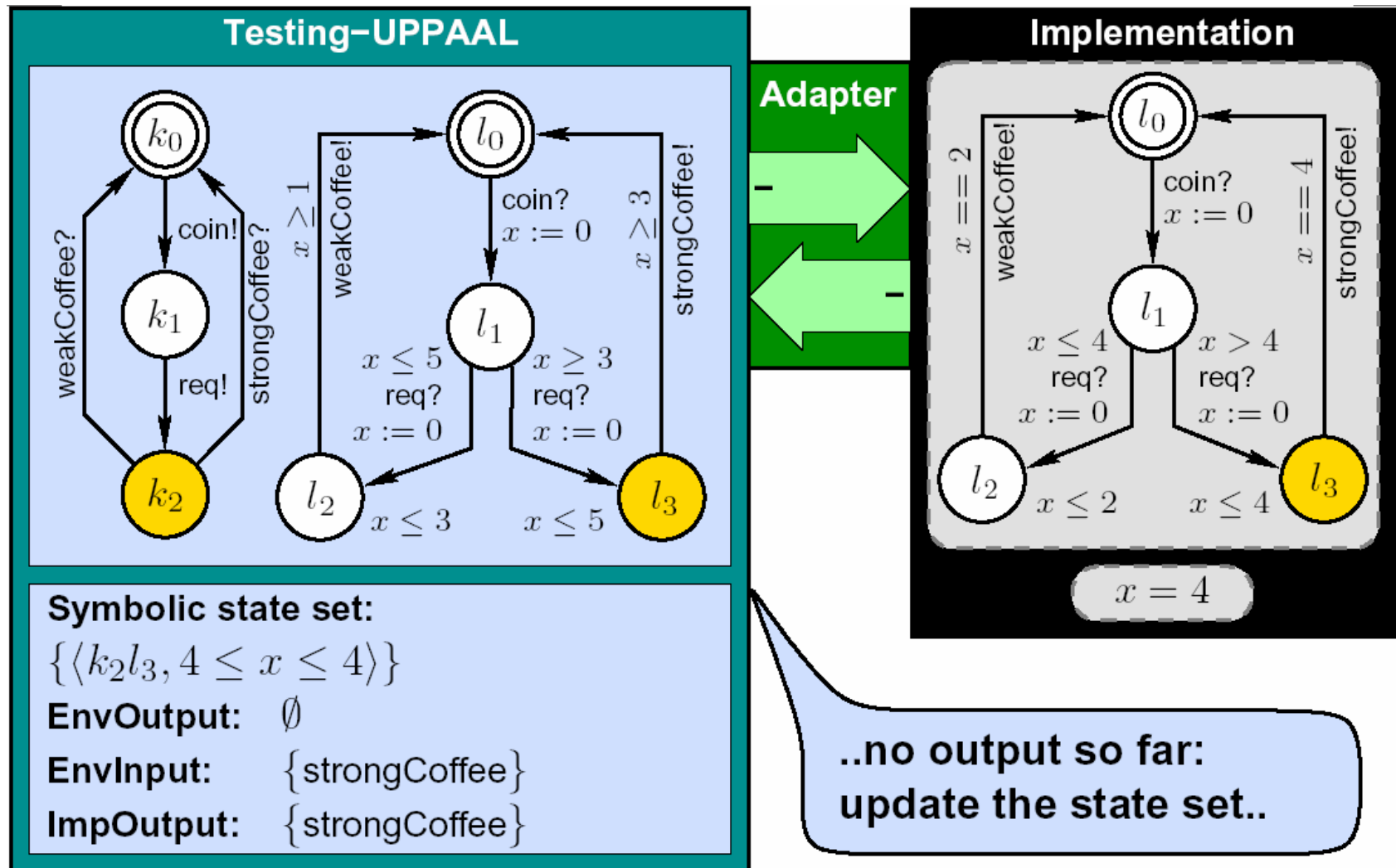


Online Testing

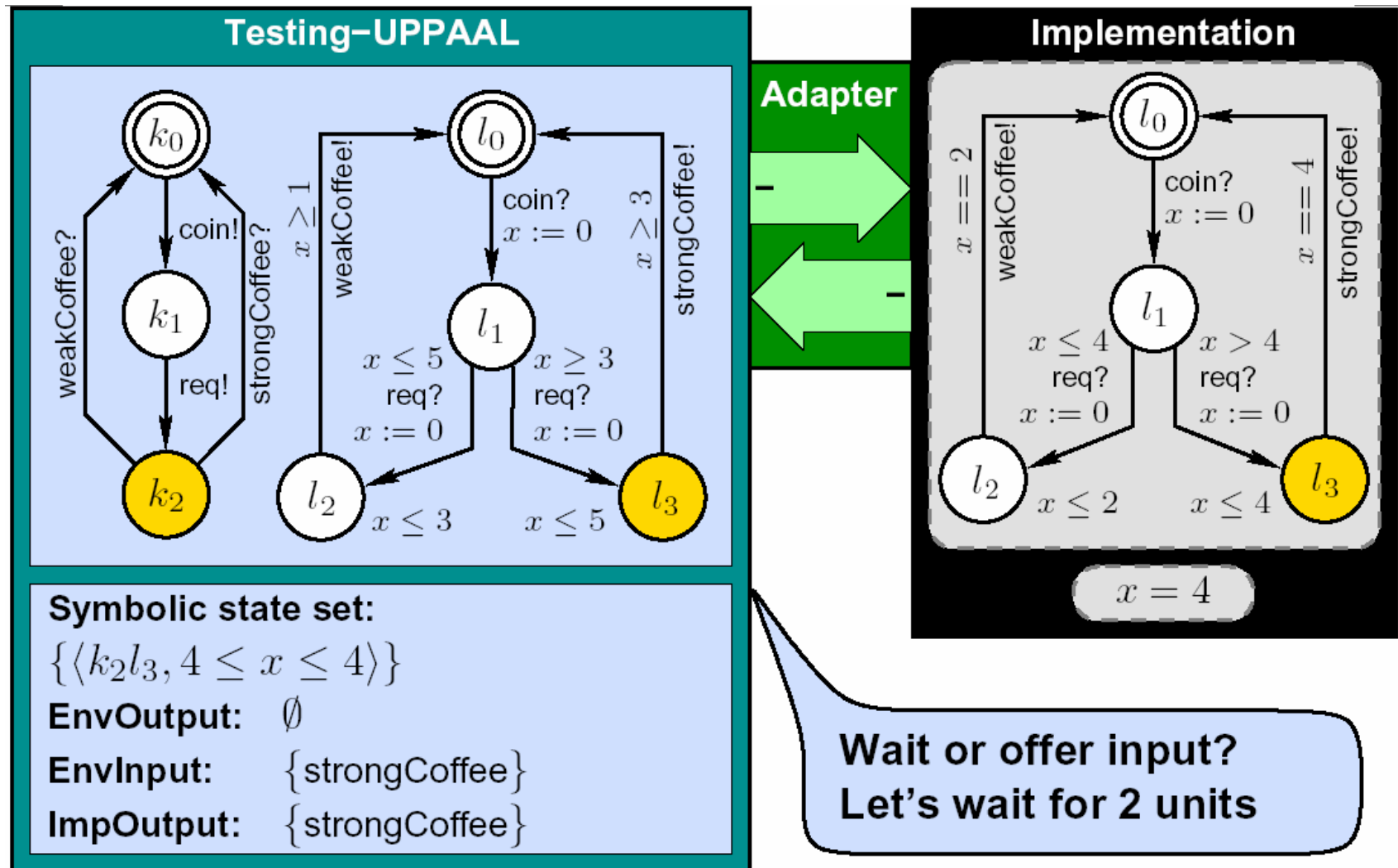


**Wait or offer input?
Let's wait for 4 units**

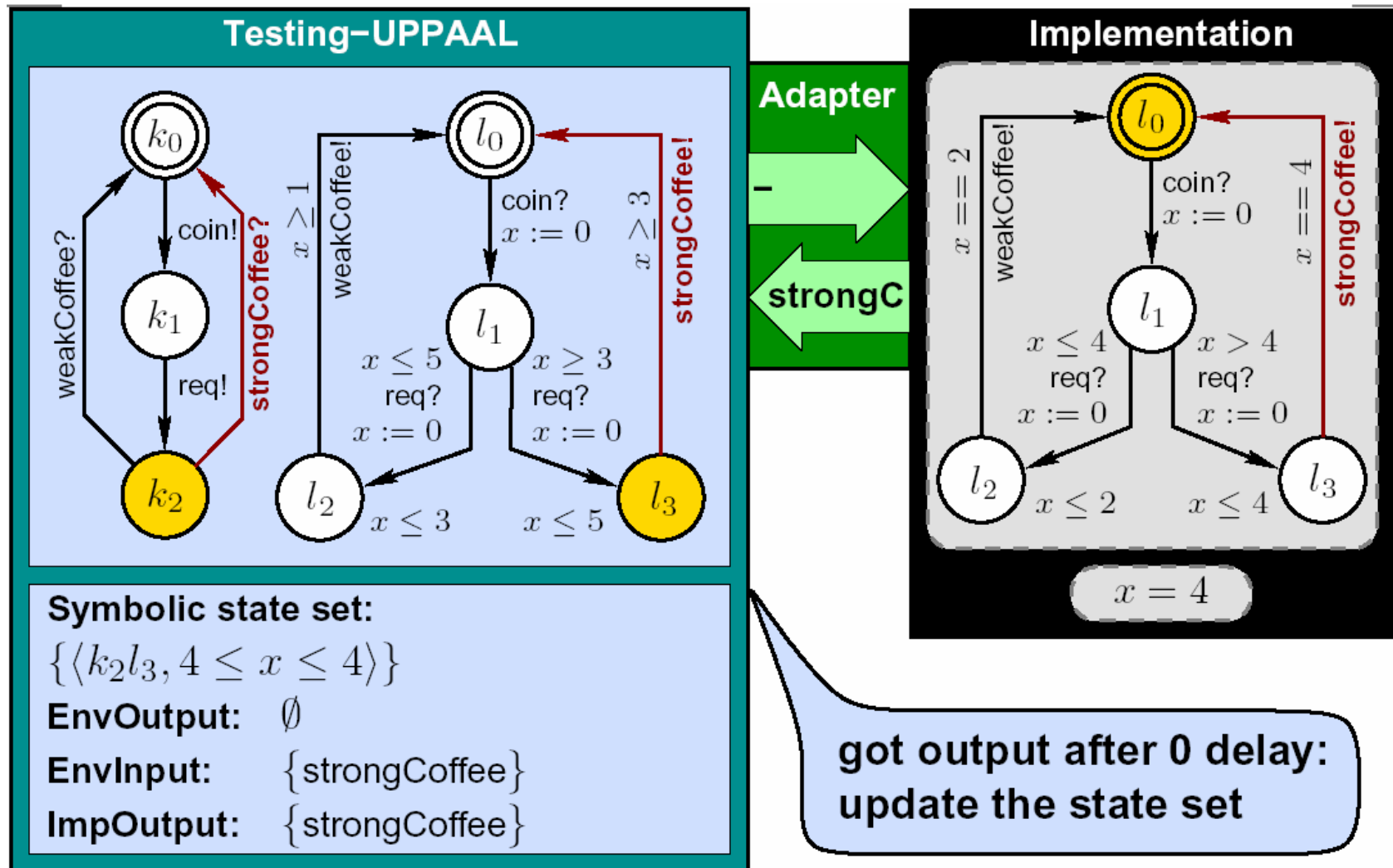
Online Testing



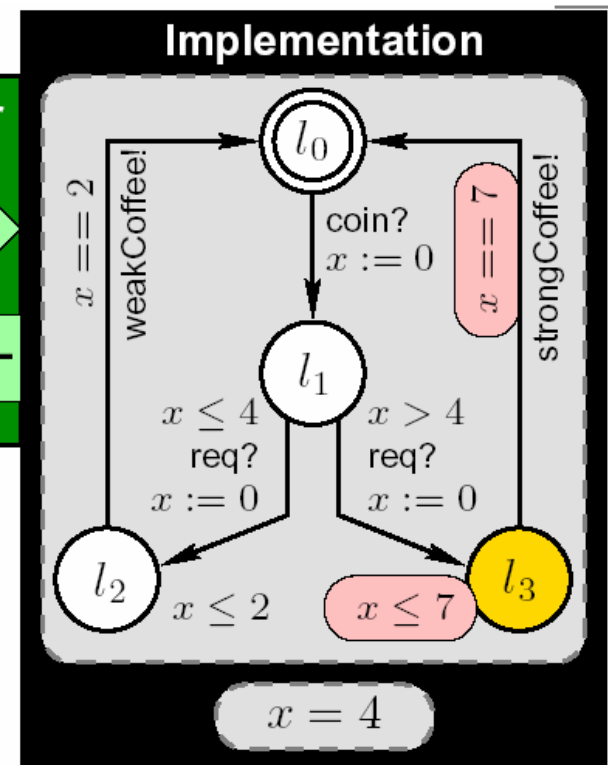
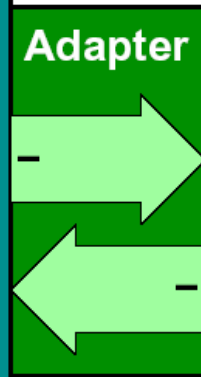
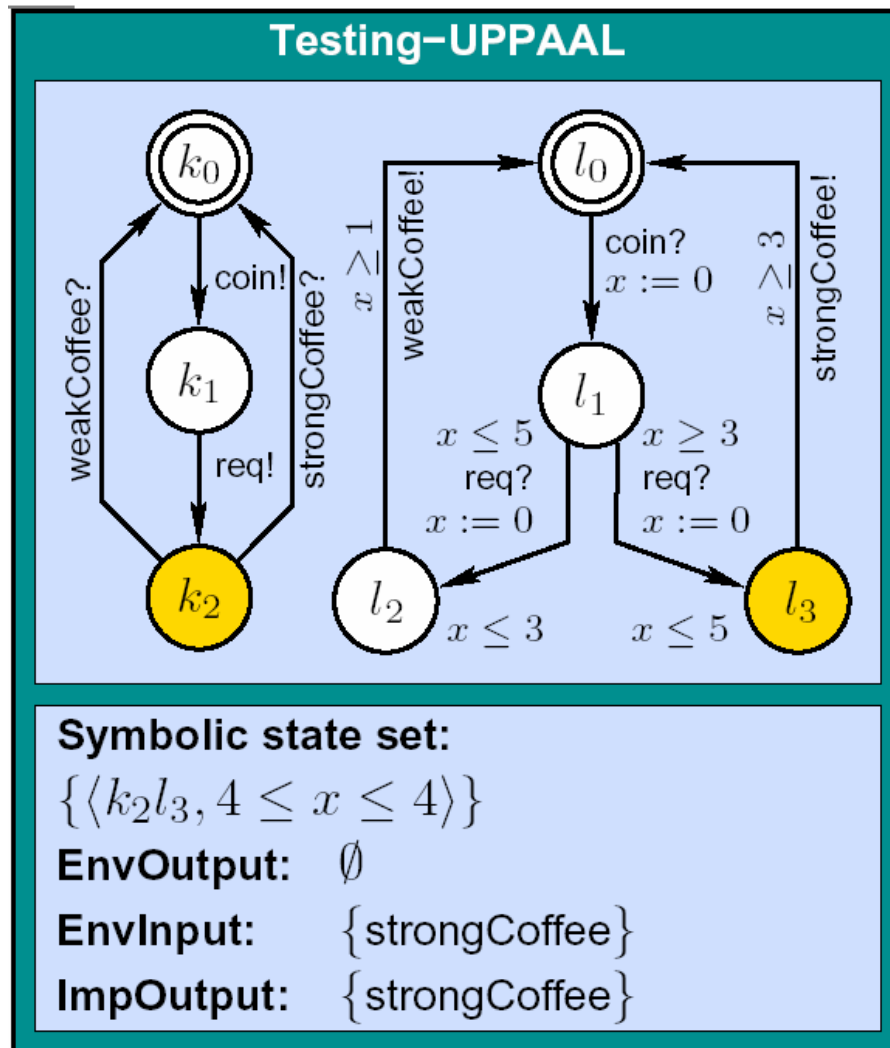
Online Testing



Online Testing

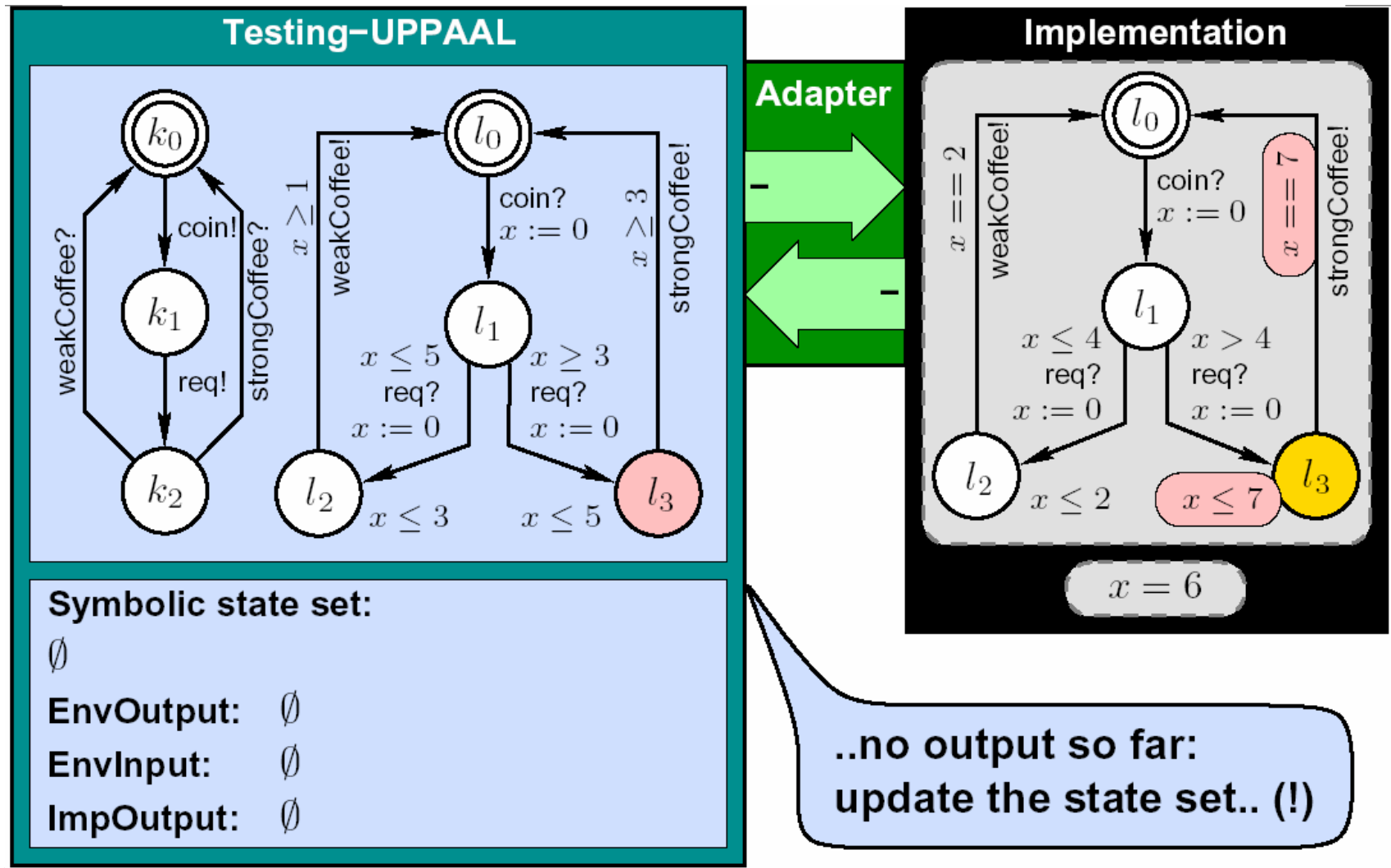


Online Testing



(what if there is a bug?)
Let's wait for 2 units

Online Testing



Industrial Application:

Danfoss Electronic Cooling Controller



Sensor Input

- air temperature sensor
- defrost temperature sensor
- (door open sensor)

Keypad Input

- 2 buttons (~40 user settable parameters)

Output Relays

- compressor relay
- defrost relay
- alarm relay
- (fan relay)

Display Output

- alarm / error indication
- mode indication
- current calculated temperature

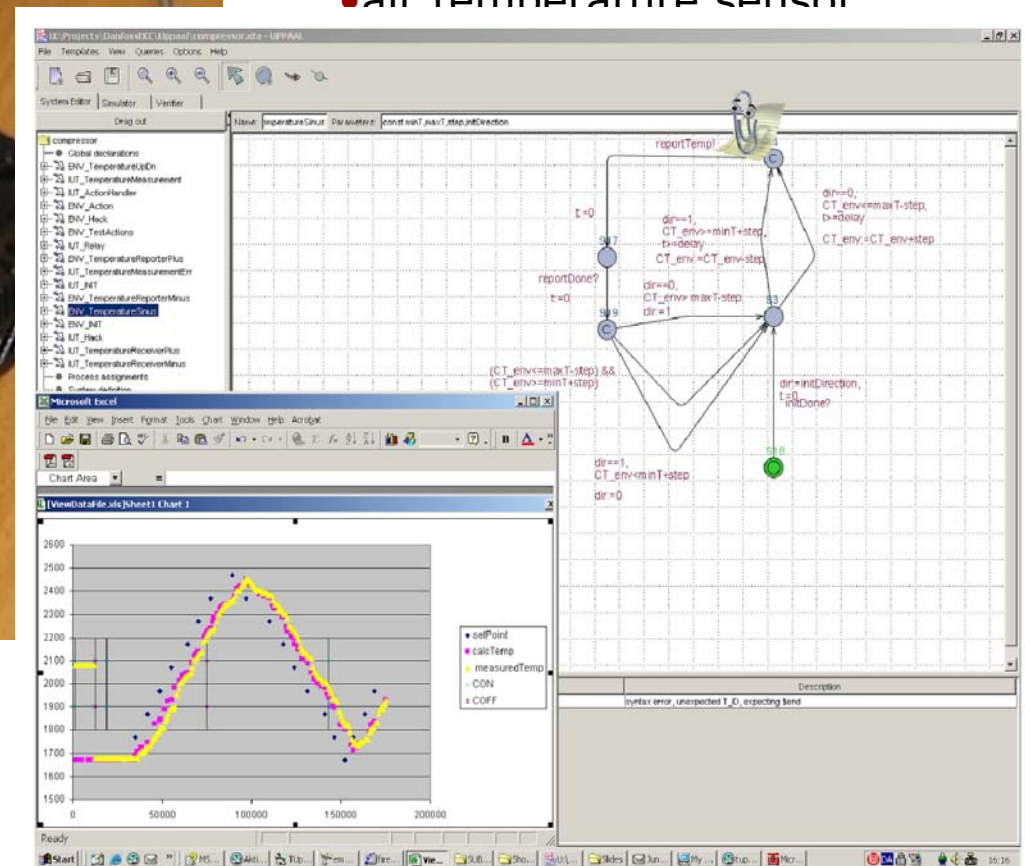
- Optional real-time clock or LON network module

Industrial Application:

Danfoss Electronic Cooling Controller

Sensor Input

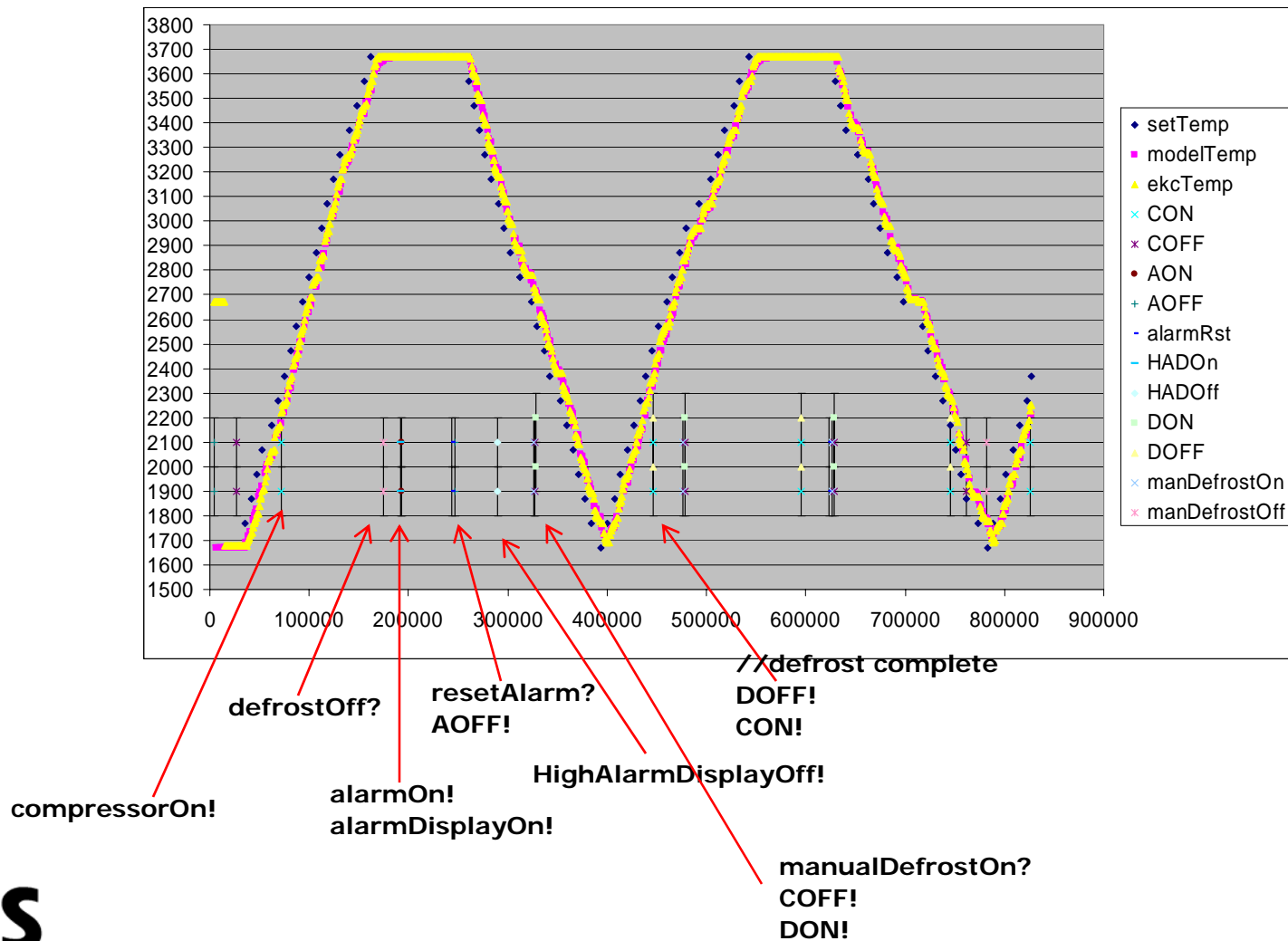
- air temperature sensor



- Optional real-time clock or LON network module

Example Test Run

(log visualization)



Model-based Testing of Real Time Systems

Conclusions



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Conclusions

- Testing real-time systems is theoretically and practically challenging
- Promising techniques and tools
- Explicit environment modeling
 - Realism and guiding
 - Separation of concerns
 - Modularity
 - Creative tool uses
 - Theoretical properties
- Real-time online testing from timed automata is feasible, but
 - Many open research issues

Research Problems

- Testing Theory
- Timed games with partial observability
- Hybrid extensions
- Other Quantitative Properties
- Probabilistic Extensions, Performance testing
- Efficient data structures and algorithms for state set computation
- Diagnosis & Debugging
- Guiding and Coverage Measurement
- Real-Time execution of TRON
- Adaptor Abstraction, IUT clock synchronization
- Further Industrial Cases

Related Work

- Formal Testing Frameworks
 - [Brinksma, Tretmans]
- Real-Time Implementation Relations
 - [Khoumsi'03, Briones'04, Krichen'04]
- Symbolic Reachability analysis of Timed Automata
 - [Dill'89, Larsen'97,...]
- Online state-set computation
 - [Tripakis'02]
- Online Testing
 - [Tretmans'99, Peleska'02, Krichen'04]